

## TOTAL DOSE RADIATION TEST REPORT

<b>Part Type : BI06</b>
<b>Package : TO-39</b>
<b>Description : Transistors - Low power PNP</b>
<b>Manufacturer : STMicroelectronics</b>
<b>Date Code: 30945A</b>

**Alter Italy Purchase Order N° 5503571 dated 03/26/2010**

**Alter Italy Technical Responsible: Alessandro Cavagnoli**

<b>Hirex reference :</b>	HRX/TID/0771	Issue : 01	Date :	March 29 <sup>th</sup> , 2010
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Hirex Engineering	Total Dose Radiation Test Report		Ref.:	HRX/TID/0771
	BI06	STMicroelectronics	Issue:	01

**TOTAL DOSE RADIATION TEST REPORT  
on BI06  
STMicroelectronics  
Transistors - Low power PNP**

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## 1 Introduction

A total dose radiation verification test of the STMicroelectronics BI06, Transistors - Low power PNP has been performed with an accumulated dose of about 107 Krad(Si) at a dose rate of 275 rad(Si)/hour, in response to Alter Italy purchase order reference 5503571.

The purpose of this test was to evaluate total dose withstanding of this component, to investigate its suitability for being used in space applications. This test was conducted on samples provided by Alter Italy.

Test has been performed in accordance with Hirex Engineering proposal reference HRX/PRO/2906 Issue 01 dated 12/09/2009.

A complete set of electrical measurements together with graphical representation of measured parameters with respect to total dose received, are provided for all samples.

## 2 Applicable and Reference Documents

### 2.1 Applicable Documents

- Hirex Engineering proposal: HRX/PRO/2906 Issue 01 dated 12/09/2009
- Alter Italy specification: TPR/PL/STM/1151 issue 01 dated 12/17/2009.

### 2.2 Reference Documents

- NA

## 3 Test Samples

6 samples of the BI06 device were tested (5 ON + 1 control sample).

Samples were allocated into the bias conditions during exposures and annealing as provided in the following table.

Serial Number	Allocation
1	Control
2	Biased ON
3	Biased ON
4	Biased ON
5	Biased ON
6	Biased ON

Identification of the BI06 is given below:

**Part Number:** BI06

**Top Marking:** BI06 logo 30945A FR serial

**Diffusion Lot:**

**Date Code:** 30945A

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## 4 Experimental Conditions

### 4.1 Radiation Source Dose Rate and Annealing

The dose exposures were performed at ENEA in the Calliope plant located at the CASACCIA research centre in ROME (Italy).

The  $\gamma$  irradiation plant is a pool-type irradiation facility equipped with a  $^{60}\text{Co}$  gamma source in a large shielded panoramic room. The storage water pool, that houses the source, has dimensions of 2x4.4x8 m<sup>3</sup>.

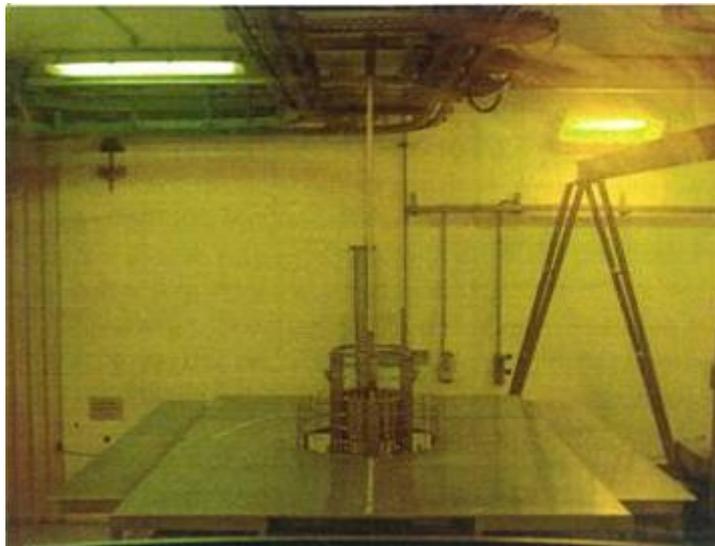
The emitted radiation has two photons of 1.173 and 1.332 MeV working in coincidence with a mean photon's energy of 1.25 MeV.

It is possible to vary the dose rate by simply adjusting the distance of devices under test to the source in a range of a few rad/H up to 2 Mrad/H.

The main Calliope features are reported in the table and Figure 1 below.

Source:	$^{60}\text{Co}$
Geometry:	Cylindrical rack with radioisotope pencils placed on two levels of external rack surface
Emitted radiation:	2 $\gamma$ photons emitted in coincidence
Photons Energy:	1.173 and 1.332 MeV (average 1.25 MeV)
Max licensed activity:	$3.7 \times 10^{15}$ Bq (100 kCi)
Dose rate range:	Few rad/h up to 2 Mrad/h

**Table 1 : Calliope main features**



**Figure 1 : View of the  $^{60}\text{Co}$   $\gamma$  source through the yellow lead window of the control room**

The irradiation conditions used for this test are provided in the following table:

Irradiation Steps	Dose rate	Annealing steps	Temperature
krams	krams/h	Hours	°C
0			
25.9	0.275		Room
51.7	0.275		Room
77.5	0.275		Room
107.9	0.275		Room
		24	Room
		168	100

## 4.2 Bias during Dose Exposures and Measurements conditions

### 4.2.1 Bias conditions

During exposures test board allowed to bias 5 samples in accordance with the electrical circuit provided in Figure 1.

During annealing steps the same stress conditions were applied at 25°C and 100°C temperatures.

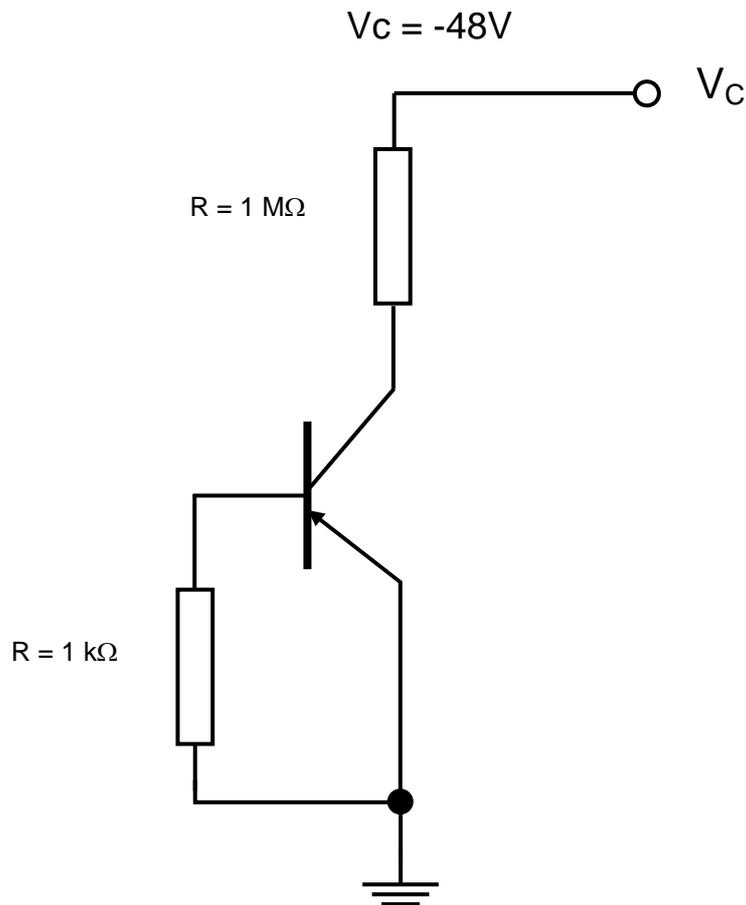


Figure 2 : Bias Conditions during Irradiation Exposures and Annealing

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4.2.2 Electrical Measurements

Electrical parameters test program principle for BI06 is provided in Figure 2.

One HP4142 DC tester was used to perform required measurements.

A dedicated test fixture was designed to ensure proper measurement conditions. In addition a faraday cage was used to ensure optimum conditions for low level measurements.

Test results were automatically loaded in an Excel worksheet and compared in real time to specification limits.

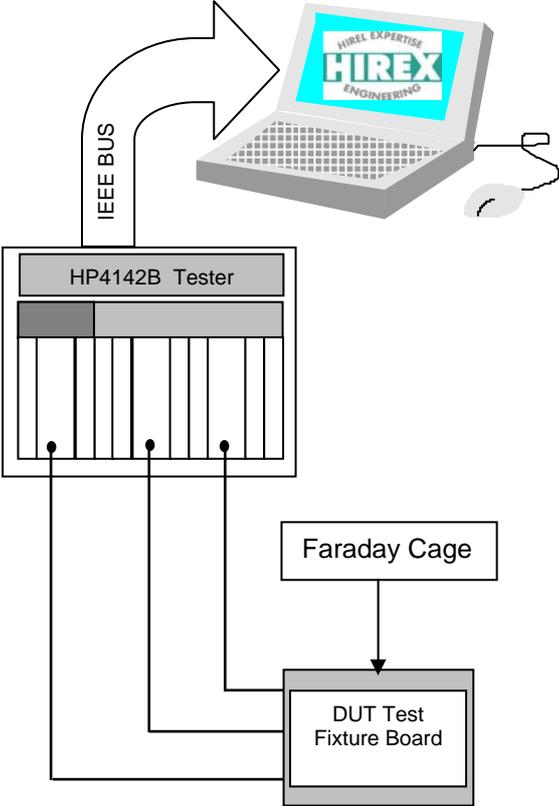


Figure 3 : BI06 test program principle

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Electrical parameters test conditions and limits used for performing this test are given in the following table.

PARAMETERS	SYMBOLS	TEST CONDITIONS	MIN	MAX	UNITS
Collector emitter voltage base open	<a href="#">V(BR)CEO</a>	Ic = -100mA		-60.0	V
Collector base cut off current	<a href="#">ICBO</a>	Vcb = -60V	-100.0E-09		A
Emitter base cut off current	<a href="#">IEBO</a>	Veb = -6V	-100.0E-09		A
Forward current transfer ratio 1	<a href="#">HFE1</a>	Vce = -2V ; Ic = -100nA	10.00		-
Forward current transfer ratio 2	<a href="#">HFE2</a>	Vce = -2V ; Ic = -1μA	10.00		-
Forward current transfer ratio 3	<a href="#">HFE3</a>	Vce = -2V ; Ic = -100μA	10.00		-
Forward current transfer ratio 4	<a href="#">HFE4</a>	Vce = -2V ; Ic = -1mA	10.00		-
Forward current transfer ratio 5	<a href="#">HFE5</a>	Vce = -2V ; Ic = -10mA	10.00		-
Forward current transfer ratio 6	<a href="#">HFE6</a>	Vce = -2V ; Ic = -100mA	80.00		-
Forward current transfer ratio 7	<a href="#">HFE7</a>	Vce = -2V ; Ic = -500mA	10.00		-
Forward current transfer ratio 8	<a href="#">HFE8</a>	Vce = -2V ; Ic = -1A	160.00	400.00	-
Forward current transfer ratio 9	<a href="#">HFE9</a>	Vce = -2V ; Ic = -2A	10.00		-
Collector emitter saturation voltage	<a href="#">VCE(SAT)1</a>	Ic = -2A ; Ib = -100mA	-400.0E-03		V
Collector emitter saturation voltage	<a href="#">VCE(SAT)2</a>	Ic = -3A ; Ib = -150mA	-600.0E-03		V
Base emitter saturation voltage	<a href="#">VBE(SAT)</a>	Ic = -2A ; Ib = -100mA	-1.2		V
Base emitter voltage	<a href="#">VBE1</a>	Vce = -2V ; Ic = -100nA	-1.5		V
Base emitter voltage	<a href="#">VBE2</a>	Vce = -2V ; Ic = -1μA	-1.5		V
Base emitter voltage	<a href="#">VBE3</a>	Vce = -2V ; Ic = -100μA	-1.5		V
Base emitter voltage	<a href="#">VBE4</a>	Vce = -2V ; Ic = -1mA	-1.5		V
Base emitter voltage	<a href="#">VBE5</a>	Ic = -100mA		-60.0	V
Base emitter voltage	<a href="#">VBE6</a>	Vcb = -60V	-100.0E-09		V
Base emitter voltage	<a href="#">VBE7</a>	Veb = -6V	-100.0E-09		V
Base emitter voltage	<a href="#">VBE8</a>	Vce = -2V ; Ic = -100nA	10.00		V
Base emitter voltage	<a href="#">VBE9</a>	Vce = -2V ; Ic = -1μA	10.00		V

**Table 2 : Measured electrical parameters**

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## 5 Conclusion

A Total Ionizing Dose verification test was carried out by Hirex Engineering under Alter Italy contract on the STMicroelectronics BI06 Transistors - Low power PNP in TO-39 package. 5 samples plus one control sample were used during testing. They were exposed to radiation using a dose rate of 275 rad(Si)/hour at room temperature.

A summary of the failure levels for each concerned parameter is provided in the following table. The behavior of each parameter is recorded for bias On samples. Parameters not listed remained within specification limits all along testing. Detail test results are presented in the following section.

Parameters	Failure Level between :		Annealing Recovery [Note 1]					Comments
			NA	No	Partial	Complete	Rebound	
<a href="#">HFE1</a>	ON samples	51.7 & 77.5 kRad(Si)				X		
<a href="#">HFE2</a>	ON samples	77.5 & 107.9 kRad(Si)				X		

[Note 1]: **NA** = Not applicable, **No**: means no sample has recovered, **Partial**: means at least one sample has recovered, **Complete**: means all samples have recovered, **Rebound**: means rebound has been observed on at least one sample.

**Table 3 : Summary of parameters failure levels**

Notes:

[1]: Complete recovery for HFE1 and HFE2 means that samples have been found within specification limits, but initial values obtained at initial readings have not been recovered.

[2]: SN 6 was send back to Alter Italy on his demand after 107 kRad(Si) exposur step. Consequently, there is no data on this sample after 24h and 168h annealing steps.

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## 6 Test Results

Test results including tables and graphics are provided in this section for each measured parameter.

Failed values with respect to specified limits are highlighted in bold red font in the tables.

Post irradiation values are calculated using 3σ approach.

- For positive variation  $(X)_{LOT+} = \text{mean}(X) + 3 \times \sigma(X)$
- For negative variation  $(X)_{LOT-} = \text{mean}(X) - 3 \times \sigma(X)$
- $(X)_{LOT \text{ WORST CASE}} = \text{Worstcase}((X)_{LOT+}, (X)_{LOT-})$

Post irradiation parameters drifts (noted ΔX) are defined as follows:

$$\Delta X = X_{\text{post rad}} - X_{\text{initial}}$$

Where  $X_{\text{post rad}}$  stands for the value of X after irradiation (at 50krads (Si), 70krads (Si) or 100krads (Si)) and  $X_{\text{initial}}$  stands for the pre-irradiation value of X.

Post irradiation drift values are calculated using 3σ approach.

- For positive variation  $\Delta(X)_{LOT+} = \text{mean}(\Delta X) + 3 \times \sigma(\Delta X)$
- For negative variation  $\Delta(X)_{LOT-} = \text{mean}(\Delta X) - 3 \times \sigma(\Delta X)$
- $\Delta(X)_{LOT \text{ WORST CASE}} = \text{Worstcase}(\Delta(X)_{LOT+}, \Delta(X)_{LOT-})$

For bipolar transistors, drifts on forward current transfer ratio are calculated as follows:

$$\Delta\left(\frac{1}{h_{FE}}\right)_{LOT} = \text{mean}\left(\Delta\frac{1}{h_{FE}}\right) + 3 \times \sigma\left(\Delta\frac{1}{h_{FE}}\right)$$

$$[h_{FE}]_{\text{POST RAD}} = \frac{1}{\Delta\left(\frac{1}{h_{FE}}\right)_{LOT} + \frac{1}{h_{FE(\text{min})}}}$$

Where σ stands for standard deviation and  $h_{FE(\text{min})}$  stands for the pre-irradiation spec minimum  $h_{FE}$  limit available in table 2.

Test conditions : TID

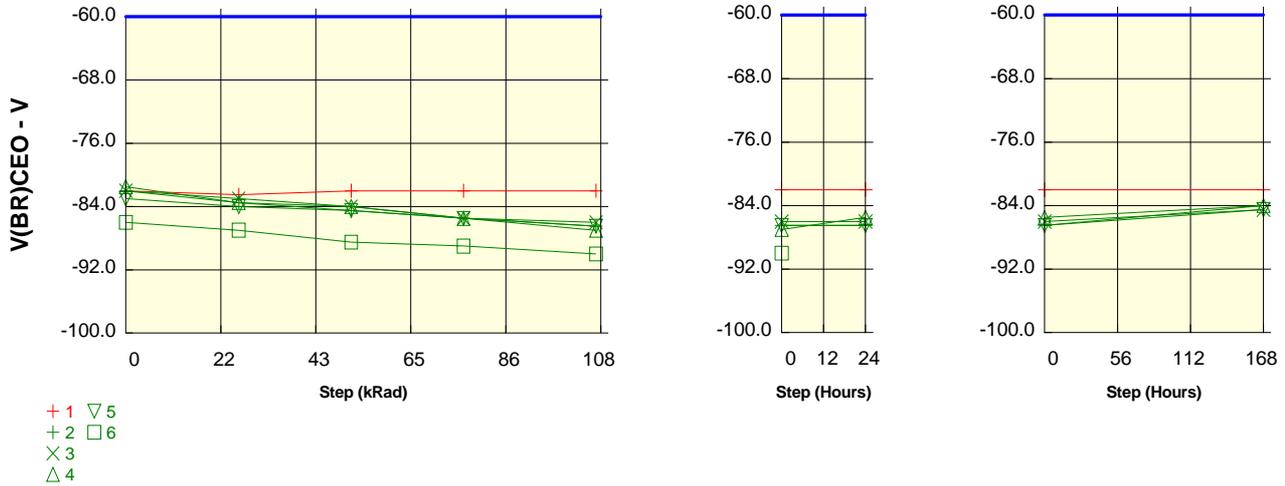
Parameter : Collector to Emitter Breakdown Voltage : V(BR)CEO

Ic = -100mA

Unit : V

Spec Limit Max : -60.0

Spec limits are represented in bold lines on the graphic.



Measurements

V(BR)CEO	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
1_REF	-82.0	-82.5	-82.0	-82.0	-82.0	-82.0	-82.0
ON samples							
2	-82.0	-83.5	-84.5	-85.5	-86.5	-86.5	-84.0
3	-82.0	-83.0	-84.0	-85.5	-86.0	-86.0	-84.5
4	-81.5	-83.5	-84.0	-85.5	-87.0	-85.5	-84.0
5	-83.0	-84.0	-84.5	-85.5	-86.5	-86.5	-84.5
6	-86.0	-87.0	-88.5	-89.0	-90.0		
Statistics							
Min	-86.0	-87.0	-88.5	-89.0	-90.0	-86.5	-84.5
Max	-81.5	-83.0	-84.0	-85.5	-86.0	-85.5	-84.0
Average	-82.9	-84.2	-85.1	-86.2	-87.2	-86.1	-84.3
Sigma	1.6	1.4	1.7	1.4	1.4	0.4	0.3
(V(B) Lot WorstCase	-78.0	-79.9	-80.0	-82.0	-82.9	-84.9	-83.5

Drift Calculation

V(BR)CEO	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
ON samples							
2	-	-1.50E+00	-2.50E+00	-3.50E+00	-4.50E+00	-4.50E+00	-2.00E+00
3	-	-1.00E+00	-2.00E+00	-3.50E+00	-4.00E+00	-4.00E+00	-2.50E+00
4	-	-2.00E+00	-2.50E+00	-4.00E+00	-5.50E+00	-4.00E+00	-2.50E+00
5	-	-1.00E+00	-1.50E+00	-2.50E+00	-3.50E+00	-3.50E+00	-1.50E+00
6	-	-1.00E+00	-2.50E+00	-3.00E+00	-4.00E+00		
Average	-	-1.30E+00	-2.20E+00	-3.30E+00	-4.30E+00	-4.00E+00	-2.13E+00
Sigma	-	400.00E-03	400.00E-03	509.90E-03	678.23E-03	353.55E-03	414.58E-03
d(V(B) Lot WorstCase	-	-100.00E-03	-1.00E+00	-1.77E+00	-2.27E+00	-2.94E+00	-881.27E-03

Test conditions : TID

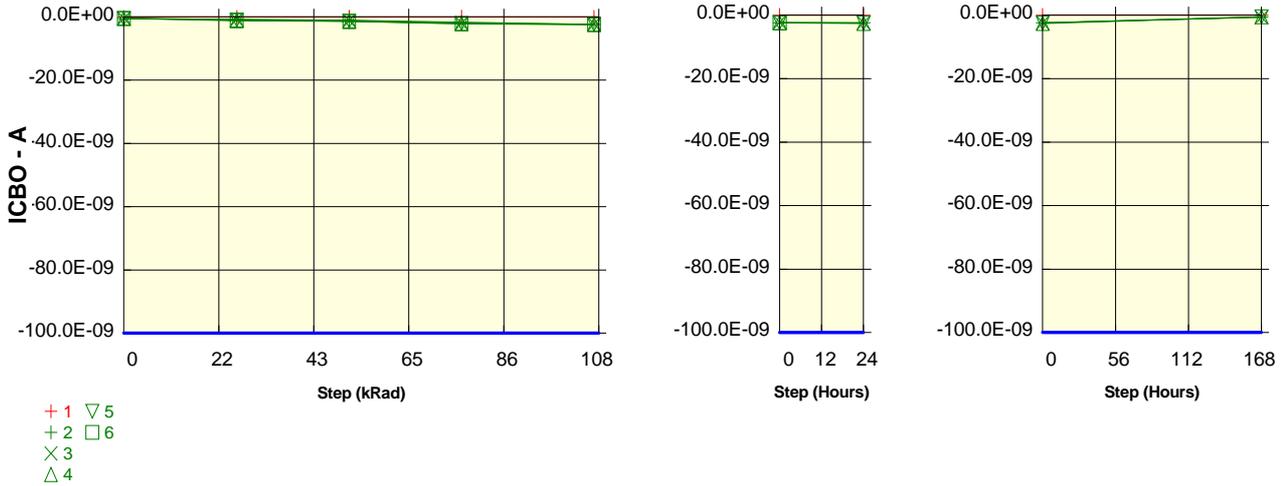
Parameter : Collector Base cut-off current : ICBO

Vcb = -60V

Unit : A

Spec Limit Min : -100.0E-09

Spec limits are represented in bold lines on the graphic.



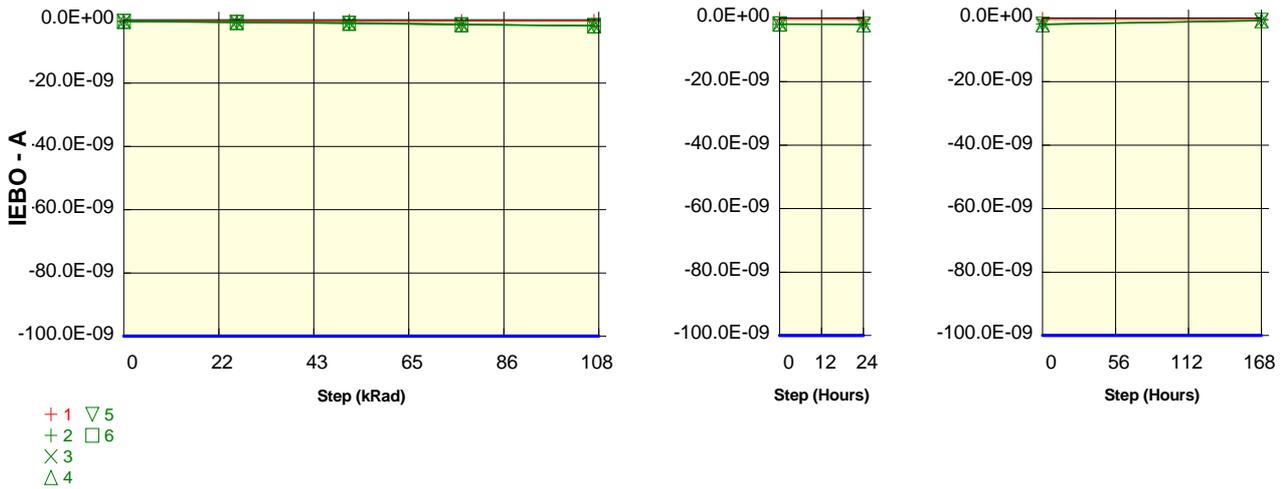
Measurements

ICBO	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
1 REF	-36.6E-12	-69.9E-12	-34.1E-12	-28.4E-12	-36.5E-12	-37.3E-12	-39.8E-12
ON samples							
2	-584.4E-12	-815.3E-12	-1.1E-09	-1.7E-09	-2.4E-09	-2.4E-09	-632.6E-12
3	-479.6E-12	-855.3E-12	-1.2E-09	-2.0E-09	-2.3E-09	-2.4E-09	-678.4E-12
4	-532.5E-12	-1.1E-09	-1.4E-09	-2.1E-09	-2.4E-09	-2.6E-09	-550.7E-12
5	-572.3E-12	-1.0E-09	-1.4E-09	-2.1E-09	-2.4E-09	-2.5E-09	-522.1E-12
6	-500.1E-12	-1.2E-09	-1.5E-09	-2.2E-09	-2.5E-09		
Statistics							
Min	-584.4E-12	-1.2E-09	-1.5E-09	-2.2E-09	-2.5E-09	-2.6E-09	-678.4E-12
Max	-479.6E-12	-815.3E-12	-1.1E-09	-1.7E-09	-2.3E-09	-2.4E-09	-522.1E-12
Average	-533.8E-12	-1.0E-09	-1.3E-09	-2.0E-09	-2.4E-09	-2.5E-09	-595.9E-12
Sigma	40.3E-12	156.1E-12	140.3E-12	187.9E-12	68.2E-12	90.8E-12	62.5E-12
d(ICB) Lot WorstCase	-654.6E-12	-1.5E-09	-1.7E-09	-2.6E-09	-2.6E-09	-2.8E-09	-783.5E-12

Drift Calculation

ICBO	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
ON samples							
2	-	-230.98E-12	-515.24E-12	-1.11E-09	-1.84E-09	-1.83E-09	-48.20E-12
3	-	-375.70E-12	-723.00E-12	-1.51E-09	-1.81E-09	-1.92E-09	-198.76E-12
4	-	-574.30E-12	-824.10E-12	-1.56E-09	-1.88E-09	-2.09E-09	-18.16E-12
5	-	-429.90E-12	-840.90E-12	-1.57E-09	-1.82E-09	-1.96E-09	50.18E-12
6	-	-735.50E-12	-982.70E-12	-1.75E-09	-2.00E-09		
Average	-	-469.28E-12	-777.19E-12	-1.50E-09	-1.87E-09	-1.95E-09	-53.74E-12
Sigma	-	172.63E-12	154.95E-12	209.69E-12	69.16E-12	92.25E-12	91.00E-12
d(ICB) Lot WorstCase	-	-987.15E-12	-1.24E-09	-2.13E-09	-2.08E-09	-2.23E-09	-326.75E-12

**Test conditions : TID**  
**Parameter : Emitter Base cut-off current : IEBO**  
**Veb = -6V**  
 Unit : A  
 Spec Limit Min : -100.0E-09  
 Spec limits are represented in bold lines on the graphic.



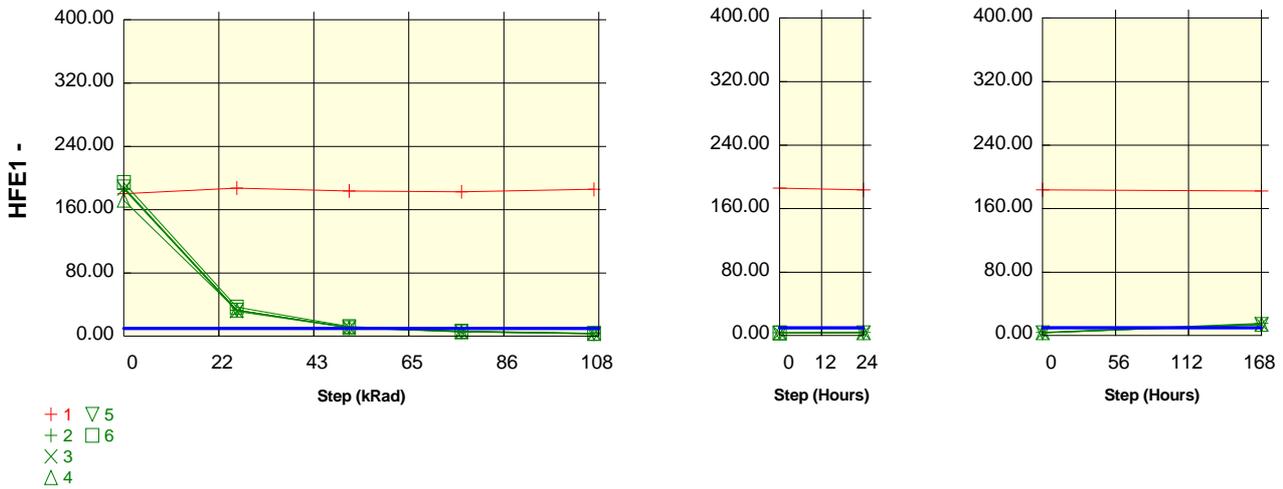
**Measurements**

IEBO	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>1_REF</b>	-387.2E-12	-389.1E-12	-372.6E-12	-366.6E-12	-382.0E-12	-371.6E-12	-375.6E-12
<b>ON samples</b>							
2	-561.5E-12	-612.5E-12	-877.2E-12	-1.3E-09	-2.0E-09	-1.9E-09	-701.6E-12
3	-561.7E-12	-709.3E-12	-1.0E-09	-1.5E-09	-1.8E-09	-1.9E-09	-805.6E-12
4	-591.5E-12	-933.3E-12	-1.2E-09	-1.6E-09	-1.9E-09	-2.1E-09	-852.2E-12
5	-543.7E-12	-785.7E-12	-1.1E-09	-1.6E-09	-1.8E-09	-1.9E-09	-717.9E-12
6	-445.6E-12	-811.2E-12	-1.1E-09	-1.5E-09	-1.8E-09		
<b>Statistics</b>							
<b>Min</b>	-591.5E-12	-933.3E-12	-1.2E-09	-1.6E-09	-2.0E-09	-2.1E-09	-852.2E-12
<b>Max</b>	-445.6E-12	-612.5E-12	-877.2E-12	-1.3E-09	-1.8E-09	-1.9E-09	-701.6E-12
<b>Average</b>	-540.8E-12	-770.4E-12	-1.1E-09	-1.5E-09	-1.9E-09	-2.0E-09	-769.3E-12
<b>Sigma</b>	50.0E-12	106.9E-12	106.7E-12	119.4E-12	70.3E-12	87.8E-12	62.1E-12
<b>(IEB) Lot WorstCase</b>	-690.9E-12	-1.1E-09	-1.4E-09	-1.9E-09	-2.1E-09	-2.2E-09	-955.6E-12

**Drift Calculation**

IEBO	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
2	-	-51.02E-12	-315.72E-12	-715.28E-12	-1.39E-09	-1.31E-09	-140.08E-12
3	-	-147.54E-12	-464.68E-12	-915.68E-12	-1.21E-09	-1.35E-09	-243.92E-12
4	-	-341.88E-12	-605.74E-12	-1.03E-09	-1.35E-09	-1.51E-09	-260.76E-12
5	-	-241.94E-12	-571.46E-12	-1.01E-09	-1.29E-09	-1.39E-09	-174.14E-12
6	-	-365.66E-12	-636.44E-12	-1.10E-09	-1.39E-09		
<b>Average</b>	-	-229.61E-12	-518.81E-12	-955.20E-12	-1.33E-09	-1.39E-09	-204.72E-12
<b>Sigma</b>	-	118.23E-12	116.91E-12	133.21E-12	69.31E-12	75.30E-12	49.47E-12
<b>d(IEB) Lot WorstCase</b>	-	-584.31E-12	-869.54E-12	-1.35E-09	-1.53E-09	-1.62E-09	-353.15E-12

**Test conditions : TID**  
**Parameter : Forward current transfer ratio 1 : HFE1**  
**Vce = -2V ; Ic = -100nA**  
 Unit :  
 Spec Limit Min : 10.00  
 Spec limits are represented in bold lines on the graphic.



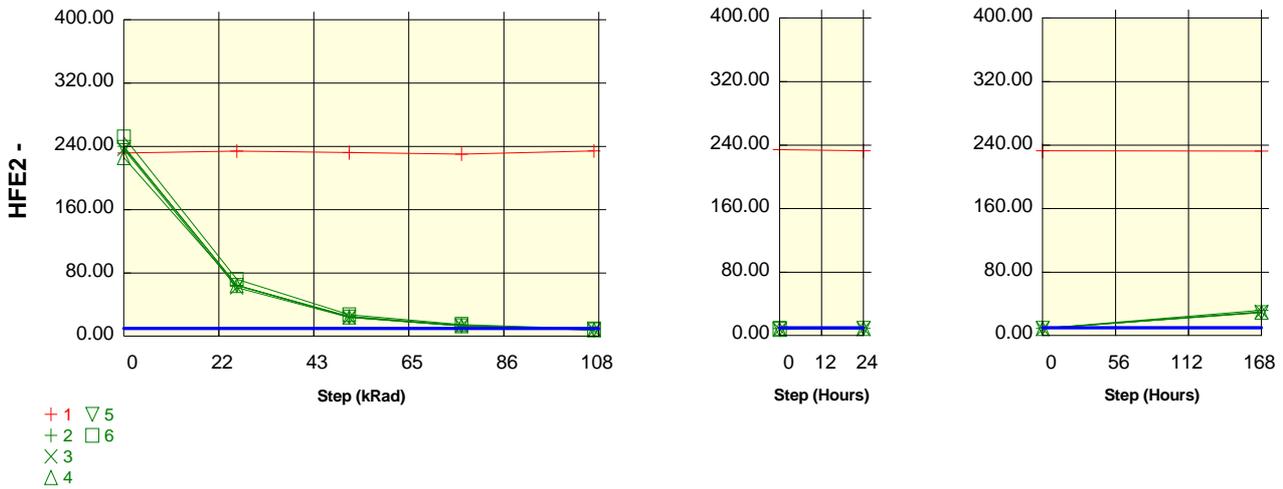
**Measurements**

HFE1	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
1 REF	180.08	187.28	183.59	182.65	185.59	183.56	182.17
<b>ON samples</b>							
2	186.39	32.64	11.19	<b>6.19</b>	<b>3.60</b>	<b>3.83</b>	15.52
3	186.66	31.46	10.66	<b>5.52</b>	<b>3.19</b>	<b>3.57</b>	14.53
4	171.82	32.78	10.87	<b>5.57</b>	<b>3.23</b>	<b>3.72</b>	13.97
5	188.62	32.98	10.90	<b>5.58</b>	<b>3.24</b>	<b>3.70</b>	13.80
6	194.22	36.72	12.37	<b>6.35</b>	<b>3.69</b>		
<b>Statistics</b>							
Min	171.82	31.46	10.66	5.52	3.19	3.57	13.80
Max	194.22	36.72	12.37	6.35	3.69	3.83	15.52
Average	185.54	33.32	11.20	5.84	3.39	3.70	14.45
Sigma	7.42	1.78	0.61	0.35	0.21	0.09	0.67
(HFE) Lot WorstCase	163.30	27.96	9.37	4.78	2.76	3.43	12.44

**Drift Calculation**

HFE1	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
2	-	25.27E-03	83.99E-03	156.11E-03	272.38E-03	255.87E-03	59.09E-03
3	-	26.43E-03	88.47E-03	175.71E-03	307.86E-03	274.50E-03	63.49E-03
4	-	24.69E-03	86.17E-03	173.61E-03	303.61E-03	263.35E-03	65.77E-03
5	-	25.02E-03	86.41E-03	174.03E-03	303.82E-03	264.79E-03	67.18E-03
6	-	22.08E-03	75.68E-03	152.40E-03	265.77E-03		
Average	-	24.70E-03	84.14E-03	166.37E-03	290.69E-03	264.63E-03	63.88E-03
Sigma	-	1.43E-03	4.46E-03	9.99E-03	17.83E-03	6.63E-03	3.07E-03
d(1/HFE) Lot WorstCase	-	29.00E-03	97.54E-03	196.34E-03	344.19E-03	284.51E-03	73.08E-03

**Test conditions : TID**  
**Parameter : Forward current transfer ratio 2 : HFE2**  
**Vce = -2V ; Ic = -1µA**  
 Unit :  
 Spec Limit Min : 10.00  
 Spec limits are represented in bold lines on the graphic.



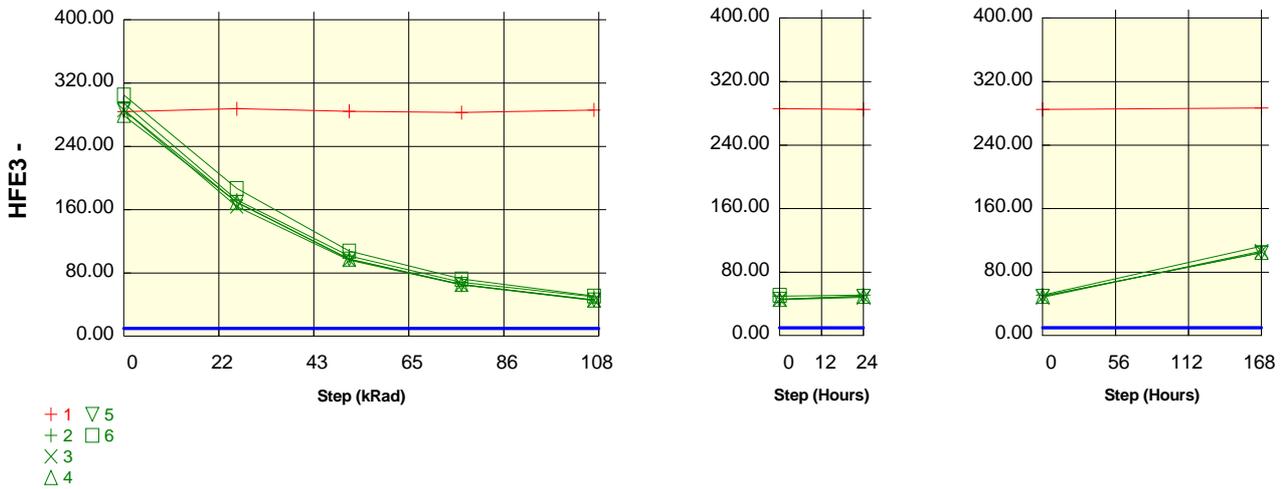
**Measurements**

HFE2	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
1 REF	231.58	233.96	232.11	230.19	234.25	232.80	232.39
<b>ON samples</b>							
2	240.20	64.44	25.08	13.64	8.77	9.27	32.03
3	236.81	61.68	23.78	13.06	7.92	8.69	30.06
4	225.82	64.16	24.16	13.16	7.93	9.01	29.26
5	238.68	64.39	24.19	13.15	8.01	9.00	29.04
6	251.97	71.88	27.27	14.82	9.06		
<b>Statistics</b>							
Min	225.82	61.68	23.78	13.06	7.92	8.69	29.04
Max	251.97	71.88	27.27	14.82	9.06	9.27	32.03
Average	238.70	65.31	24.90	13.57	8.34	8.99	30.10
Sigma	8.34	3.44	1.26	0.66	0.48	0.20	1.18
(HFE) Lot WorstCase	213.68	54.98	21.11	11.59	6.90	8.38	26.56

**Drift Calculation**

HFE2	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
2	-	11.36E-03	35.71E-03	69.14E-03	109.83E-03	103.74E-03	27.06E-03
3	-	11.99E-03	37.83E-03	72.35E-03	122.08E-03	110.82E-03	29.05E-03
4	-	11.16E-03	36.97E-03	71.57E-03	121.68E-03	106.53E-03	29.74E-03
5	-	11.34E-03	37.16E-03	71.86E-03	120.58E-03	106.93E-03	30.25E-03
6	-	9.94E-03	32.70E-03	63.52E-03	106.44E-03		
Average	-	11.16E-03	36.07E-03	69.69E-03	116.12E-03	107.01E-03	29.03E-03
Sigma	-	669.64E-06	1.82E-03	3.28E-03	6.63E-03	2.52E-03	1.21E-03
d(1/HFE) Lot WorstCase	-	13.17E-03	41.53E-03	79.52E-03	136.00E-03	114.57E-03	32.66E-03

**Test conditions : TID**  
**Parameter : Forward current transfer ratio 3 : HFE3**  
**Vce = -2V ; Ic = -100µA**  
 Unit :  
 Spec Limit Min : 10.00  
 Spec limits are represented in bold lines on the graphic.



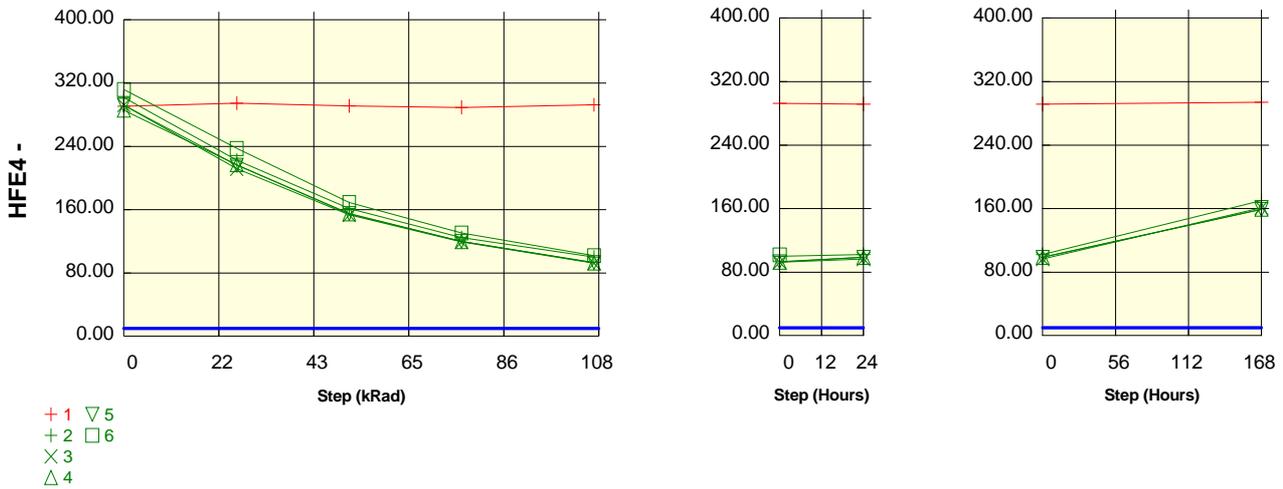
**Measurements**

HFE3	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
1 REF	284.06	287.55	284.37	282.70	286.10	284.86	286.57
<b>ON samples</b>							
2	294.69	172.30	101.57	68.24	49.79	51.11	112.54
3	285.81	163.98	96.35	65.11	45.38	48.22	106.23
4	279.22	169.28	97.31	65.47	45.74	49.59	104.73
5	286.19	169.15	97.53	65.47	45.85	49.61	104.51
6	305.02	186.73	107.54	72.18	50.73		
<b>Statistics</b>							
Min	279.22	163.98	96.35	65.11	45.38	48.22	104.51
Max	305.02	186.73	107.54	72.18	50.73	51.11	112.54
Average	290.19	172.29	100.06	67.29	47.50	49.63	107.00
Sigma	8.90	7.70	4.15	2.69	2.28	1.02	3.27
(HFE) Lot WorstCase	263.50	149.19	87.62	59.22	40.65	46.56	97.20

**Drift Calculation**

HFE3	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
2	-	2.41E-03	6.45E-03	11.26E-03	16.69E-03	16.17E-03	5.49E-03
3	-	2.60E-03	6.88E-03	11.86E-03	18.54E-03	17.24E-03	5.91E-03
4	-	2.33E-03	6.69E-03	11.69E-03	18.28E-03	16.58E-03	5.97E-03
5	-	2.42E-03	6.76E-03	11.78E-03	18.32E-03	16.66E-03	6.07E-03
6	-	2.08E-03	6.02E-03	10.58E-03	16.43E-03		
Average	-	2.37E-03	6.56E-03	11.43E-03	17.65E-03	16.66E-03	5.86E-03
Sigma	-	169.86E-06	304.32E-06	476.79E-06	898.31E-06	381.14E-06	221.24E-06
d(1/HFE) Lot WorstCase	-	2.88E-03	7.47E-03	12.86E-03	20.35E-03	17.81E-03	6.53E-03

**Test conditions : TID**  
**Parameter : Forward current transfer ratio 4 : HFE4**  
**Vce = -2V ; Ic = -1mA**  
 Unit :  
 Spec Limit Min : 10.00  
 Spec limits are represented in bold lines on the graphic.



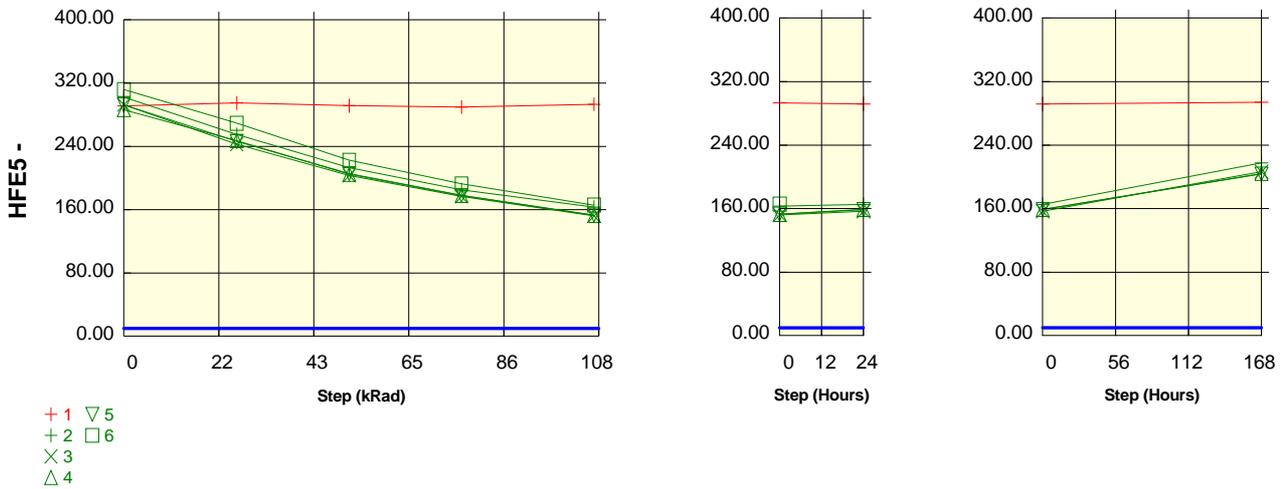
Measurements

HFE4	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
1 REF	290.82	294.65	291.13	289.20	292.62	291.70	293.82
<b>ON samples</b>							
2	301.91	222.58	161.33	124.70	100.08	102.08	170.11
3	292.29	211.61	153.34	119.04	92.31	96.53	161.04
4	285.78	216.75	154.64	119.70	92.67	98.57	159.10
5	292.24	216.21	155.20	119.82	93.12	98.67	158.89
6	311.86	237.30	169.16	130.53	101.80		
<b>Statistics</b>							
Min	285.78	211.61	153.34	119.04	92.31	96.53	158.89
Max	311.86	237.30	169.16	130.53	101.80	102.08	170.11
Average	296.82	220.89	158.73	122.76	96.00	98.96	162.29
Sigma	9.11	8.91	5.90	4.38	4.08	1.99	4.60
(HFE) Lot WorstCase	269.47	194.15	141.04	109.62	83.75	92.99	148.50

Drift Calculation

HFE4	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
2	-	1.18E-03	2.89E-03	4.71E-03	6.68E-03	6.48E-03	2.57E-03
3	-	1.30E-03	3.10E-03	4.98E-03	7.41E-03	6.94E-03	2.79E-03
4	-	1.11E-03	2.97E-03	4.86E-03	7.29E-03	6.65E-03	2.79E-03
5	-	1.20E-03	3.02E-03	4.92E-03	7.32E-03	6.71E-03	2.87E-03
6	-	1.01E-03	2.70E-03	4.45E-03	6.62E-03		
Average	-	1.16E-03	2.94E-03	4.78E-03	7.06E-03	6.70E-03	2.75E-03
Sigma	-	98.42E-06	135.04E-06	188.20E-06	341.90E-06	163.14E-06	113.37E-06
d(1/HFE) Lot WorstCase	-	1.46E-03	3.34E-03	5.35E-03	8.09E-03	7.18E-03	3.09E-03

**Test conditions : TID**  
**Parameter : Forward current transfer ratio 5 : HFE5**  
**Vce = -2V ; Ic = -10mA**  
 Unit :  
 Spec Limit Min : 10.00  
 Spec limits are represented in bold lines on the graphic.



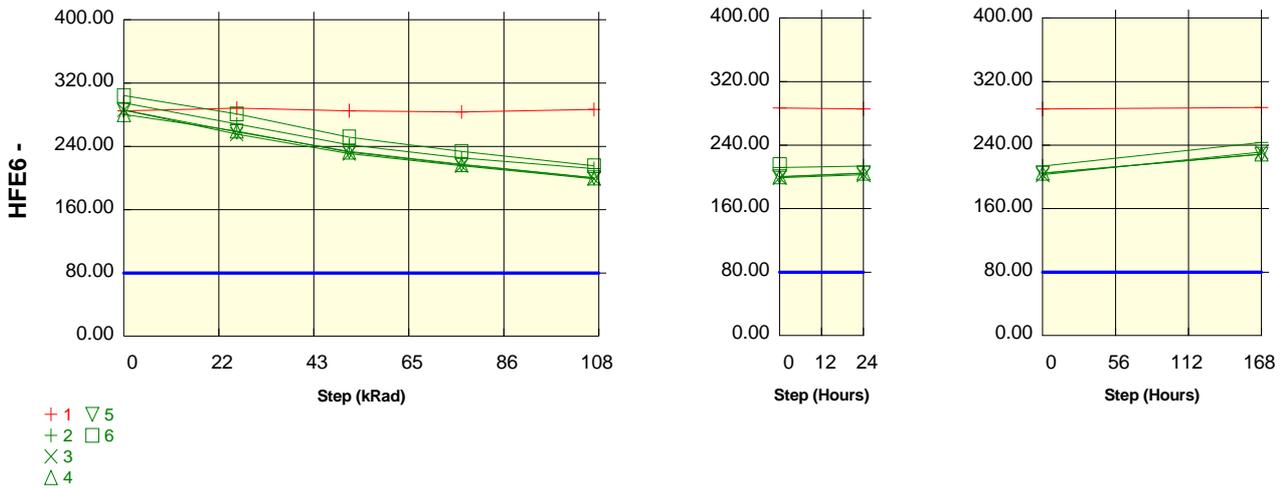
**Measurements**

HFE5	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
1 REF	291.21	294.84	291.43	289.81	293.22	291.91	293.94
<b>ON samples</b>							
2	302.13	255.14	213.15	185.16	163.22	165.34	217.58
3	292.55	242.66	203.09	176.84	152.01	156.56	206.47
4	286.38	247.16	204.69	177.78	152.63	158.73	204.08
5	292.54	246.32	205.50	178.13	153.16	158.87	203.78
6	311.88	269.23	222.38	192.51	165.76		
<b>Statistics</b>							
Min	286.38	242.66	203.09	176.84	152.01	156.56	203.78
Max	311.88	269.23	222.38	192.51	165.76	165.34	217.58
Average	297.10	252.10	209.76	182.08	157.36	159.88	207.98
Sigma	8.94	9.48	7.20	6.00	5.89	3.29	5.64
(HFE) Lot WorstCase	270.26	223.65	188.17	164.09	139.69	150.02	191.06

**Drift Calculation**

HFE5	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
2	-	609.67E-06	1.38E-03	2.09E-03	2.82E-03	2.74E-03	1.29E-03
3	-	702.75E-06	1.51E-03	2.24E-03	3.16E-03	2.97E-03	1.43E-03
4	-	554.09E-06	1.39E-03	2.13E-03	3.06E-03	2.81E-03	1.41E-03
5	-	641.51E-06	1.45E-03	2.20E-03	3.11E-03	2.88E-03	1.49E-03
6	-	507.93E-06	1.29E-03	1.99E-03	2.83E-03		
Average	-	603.19E-06	1.40E-03	2.13E-03	2.99E-03	2.85E-03	1.40E-03
Sigma	-	67.69E-06	71.78E-06	86.44E-06	144.85E-06	85.22E-06	73.37E-06
d(1/HFE) Lot WorstCase	-	806.25E-06	1.62E-03	2.39E-03	3.43E-03	3.10E-03	1.62E-03

**Test conditions : TID**  
**Parameter : Forward current transfer ratio 6 : HFE6**  
**Vce = -2V ; Ic = -100mA**  
 Unit :  
 Spec Limit Min : 80.00  
 Spec limits are represented in bold lines on the graphic.



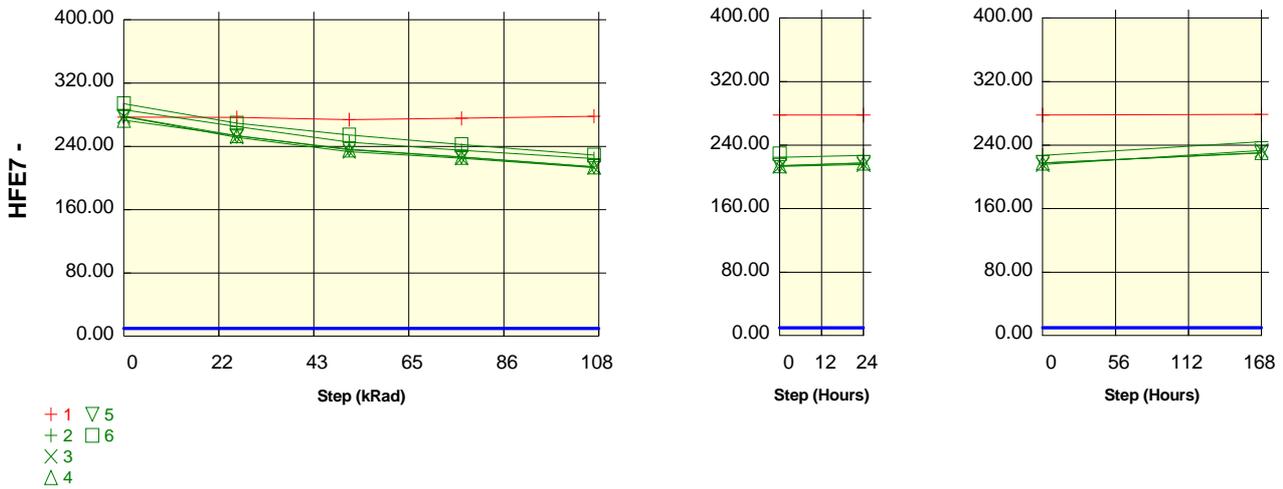
**Measurements**

HFE6	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
1 REF	284.87	288.29	285.07	283.54	286.68	285.52	287.48
<b>ON samples</b>							
2	295.16	268.37	241.88	225.42	211.88	213.54	243.37
3	285.91	255.48	230.88	215.54	198.96	202.63	231.32
4	280.29	259.40	232.71	216.67	200.01	204.52	228.83
5	285.92	258.39	233.58	217.24	200.33	204.71	228.32
6	304.22	281.19	251.76	233.63	215.51		
<b>Statistics</b>							
Min	280.29	255.48	230.88	215.54	198.96	202.63	228.32
Max	304.22	281.19	251.76	233.63	215.51	213.54	243.37
Average	290.30	264.57	238.16	221.70	205.34	206.35	232.96
Sigma	8.44	9.36	7.78	6.92	6.94	4.23	6.12
(HFE) Lot WorstCase	264.98	236.48	214.83	200.94	184.53	193.66	214.61

**Drift Calculation**

HFE6	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
2	-	338.26E-06	746.32E-06	1.05E-03	1.33E-03	1.29E-03	720.94E-06
3	-	416.67E-06	833.69E-06	1.14E-03	1.53E-03	1.44E-03	825.48E-06
4	-	287.25E-06	729.44E-06	1.05E-03	1.43E-03	1.32E-03	802.23E-06
5	-	372.64E-06	783.70E-06	1.11E-03	1.49E-03	1.39E-03	882.34E-06
6	-	269.18E-06	684.94E-06	993.09E-06	1.35E-03		
Average	-	336.80E-06	755.61E-06	1.07E-03	1.43E-03	1.36E-03	807.75E-06
Sigma	-	54.21E-06	50.30E-06	51.61E-06	76.74E-06	55.82E-06	57.98E-06
d(1/HFE) Lot WorstCase	-	499.42E-06	906.52E-06	1.22E-03	1.66E-03	1.53E-03	981.67E-06

**Test conditions : TID**  
**Parameter : Forward current transfer ratio 7 : HFE7**  
**Vce = -2V ; Ic = -500mA**  
 Unit :  
 Spec Limit Min : 10.00  
 Spec limits are represented in bold lines on the graphic.



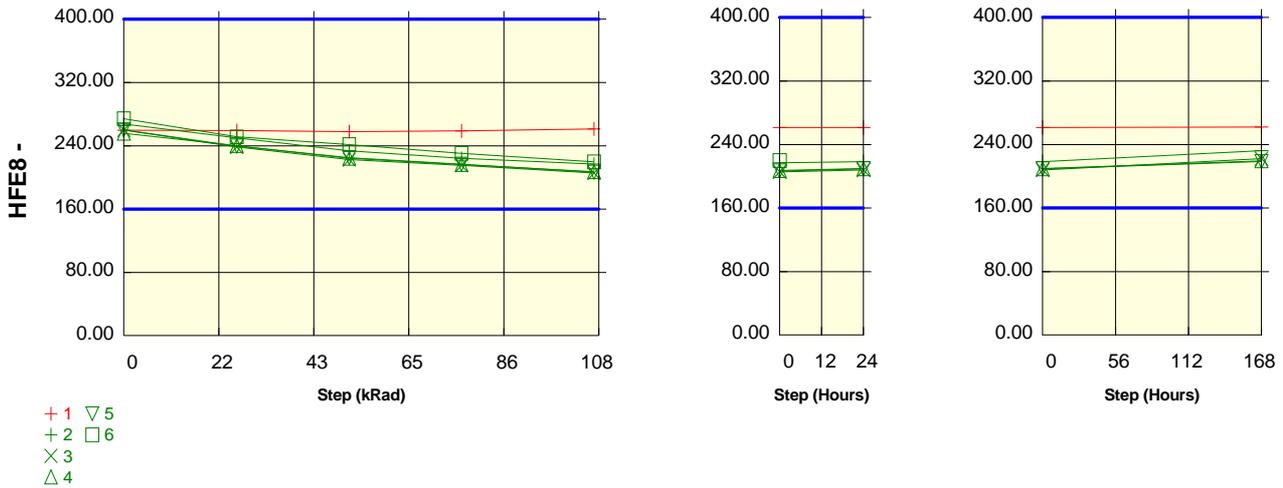
**Measurements**

HFE7	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
1 REF	277.06	276.66	273.90	275.41	278.12	277.84	278.65
<b>ON samples</b>							
2	286.25	265.10	245.36	234.86	224.47	226.87	244.30
3	277.75	251.45	233.40	225.02	213.17	215.43	233.22
4	272.99	253.49	235.57	226.19	213.83	217.34	230.51
5	277.92	253.21	236.31	226.67	214.34	217.78	229.97
6	293.92	269.26	254.32	242.11	229.05		
<b>Statistics</b>							
Min	272.99	251.45	233.40	225.02	213.17	215.43	229.97
Max	293.92	269.26	254.32	242.11	229.05	226.87	244.30
Average	281.77	258.50	240.99	230.97	218.97	219.35	234.50
Sigma	7.43	7.24	7.82	6.57	6.53	4.43	5.79
(HFE) Lot WorstCase	259.48	236.78	217.53	211.25	199.37	206.07	217.13

**Drift Calculation**

HFE7	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
2	-	278.80E-06	582.17E-06	764.48E-06	961.50E-06	914.48E-06	599.94E-06
3	-	376.54E-06	684.18E-06	843.78E-06	1.09E-03	1.04E-03	687.40E-06
4	-	281.68E-06	581.77E-06	757.96E-06	1.01E-03	937.80E-06	675.08E-06
5	-	351.14E-06	633.56E-06	813.48E-06	1.07E-03	993.74E-06	750.25E-06
6	-	311.58E-06	529.75E-06	728.16E-06	963.64E-06		
Average	-	319.95E-06	602.29E-06	781.58E-06	1.02E-03	971.91E-06	678.17E-06
Sigma	-	38.48E-06	52.48E-06	41.45E-06	52.70E-06	49.49E-06	53.41E-06
d(1/HFE) Lot WorstCase	-	435.39E-06	759.72E-06	905.92E-06	1.18E-03	1.12E-03	838.40E-06

**Test conditions : TID**  
**Parameter : Forward current transfer ratio 8 : HFE8**  
**Vce = -2V ; Ic = -1A**  
 Unit :  
 Spec Limit Min : 160.00  
 Spec Limit Max : 400.00  
 Spec limits are represented in bold lines on the graphic.



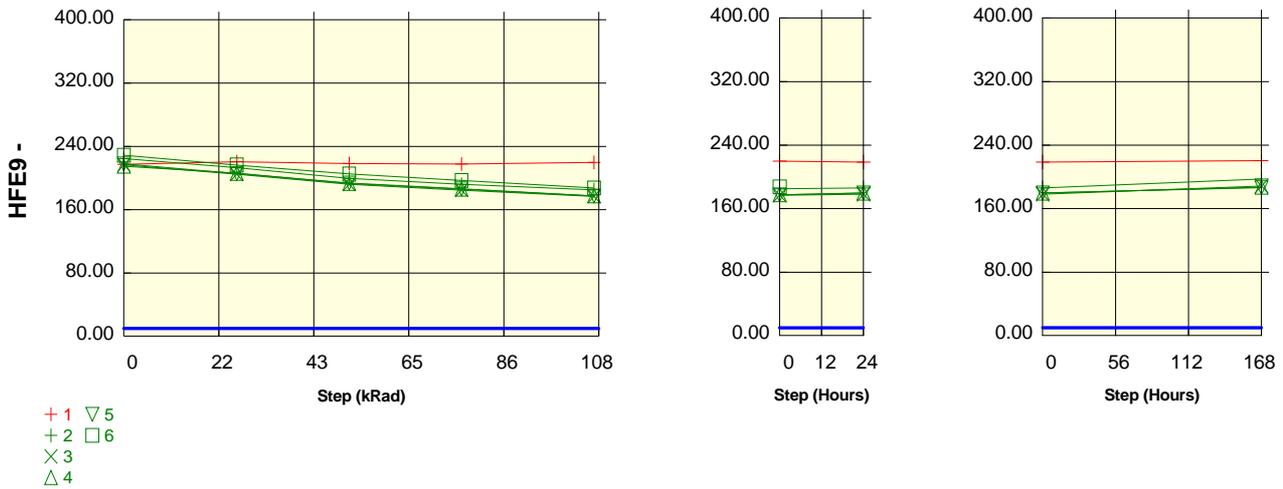
Measurements

HFE8	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
1_REF	259.52	259.22	257.82	258.79	261.34	261.34	261.92
<b>ON samples</b>							
2	267.65	249.75	233.49	224.31	216.97	218.29	232.05
3	259.94	238.40	222.53	215.27	205.60	207.89	222.19
4	255.79	240.32	224.25	216.37	207.22	209.56	219.54
5	260.21	239.67	224.85	216.71	206.65	209.44	218.73
6	274.18	251.29	241.61	230.49	219.76		
<b>Statistics</b>							
Min	255.79	238.40	222.53	215.27	205.60	207.89	218.73
Max	274.18	251.29	241.61	230.49	219.76	218.29	232.05
Average	263.56	243.88	229.35	220.63	211.24	211.29	223.13
Sigma	6.55	5.47	7.21	5.88	5.91	4.09	5.31
(HFE) Lot WorstCase	243.92	227.47	207.71	202.98	193.52	199.02	207.20

Drift Calculation

HFE8	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
2	-	267.81E-06	546.60E-06	721.87E-06	872.67E-06	844.90E-06	573.18E-06
3	-	347.68E-06	646.77E-06	798.28E-06	1.02E-03	963.18E-06	653.63E-06
4	-	251.60E-06	549.84E-06	712.23E-06	916.25E-06	862.44E-06	645.59E-06
5	-	329.37E-06	604.38E-06	771.42E-06	996.06E-06	931.62E-06	728.75E-06
6	-	332.33E-06	491.76E-06	691.37E-06	903.22E-06		
Average	-	305.76E-06	567.87E-06	739.03E-06	940.98E-06	900.54E-06	650.29E-06
Sigma	-	38.46E-06	53.16E-06	39.61E-06	55.62E-06	48.57E-06	55.08E-06
d(1/HFE) Lot WorstCase	-	421.12E-06	727.34E-06	857.87E-06	1.11E-03	1.05E-03	815.53E-06

**Test conditions : TID**  
**Parameter : Forward current transfer ratio 9 : HFE9**  
**Vce = -2V ; Ic = -2A**  
 Unit :  
 Spec Limit Min : 10.00  
 Spec limits are represented in bold lines on the graphic.



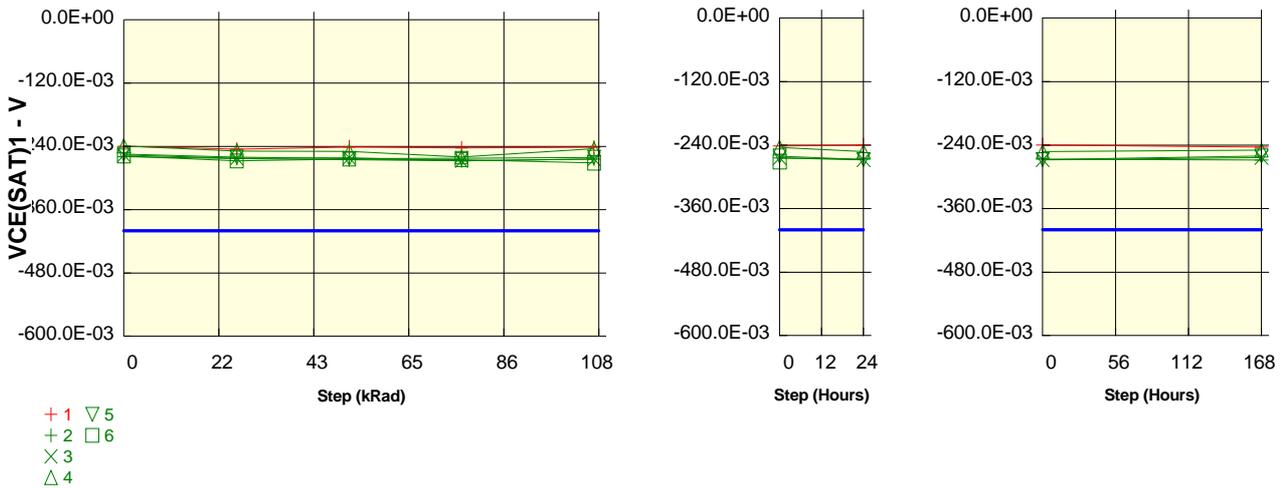
**Measurements**

HFE9	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>1 REF</b>	217.25	220.52	218.40	217.72	219.73	218.72	220.45
<b>ON samples</b>							
<b>2</b>	224.57	213.11	199.54	192.04	185.20	186.24	197.17
<b>3</b>	216.76	204.77	192.04	184.77	176.85	178.22	188.41
<b>4</b>	214.93	206.06	193.11	185.84	177.57	179.56	186.96
<b>5</b>	217.87	205.59	193.69	186.31	177.48	179.84	186.51
<b>6</b>	228.75	216.38	205.04	196.74	187.46		
<b>Statistics</b>							
<b>Min</b>	214.93	204.77	192.04	184.77	176.85	178.22	186.51
<b>Max</b>	228.75	216.38	205.04	196.74	187.46	186.24	197.17
<b>Average</b>	220.57	209.18	196.68	189.14	180.91	180.96	189.77
<b>Sigma</b>	5.22	4.68	4.93	4.56	4.49	3.11	4.33
<b>(HFE) Lot WorstCase</b>	204.90	195.15	181.90	175.45	167.45	171.65	176.76

**Drift Calculation**

HFE9	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
<b>2</b>	-	239.45E-06	558.42E-06	754.18E-06	946.45E-06	916.47E-06	618.63E-06
<b>3</b>	-	270.28E-06	594.01E-06	798.74E-06	1.04E-03	997.78E-06	694.17E-06
<b>4</b>	-	200.23E-06	525.79E-06	728.32E-06	978.87E-06	916.54E-06	695.94E-06
<b>5</b>	-	274.12E-06	572.96E-06	777.37E-06	1.04E-03	970.54E-06	771.64E-06
<b>6</b>	-	249.73E-06	505.47E-06	711.18E-06	962.92E-06		
<b>Average</b>	-	246.76E-06	551.33E-06	753.96E-06	994.78E-06	950.33E-06	695.10E-06
<b>Sigma</b>	-	26.57E-06	31.92E-06	31.75E-06	40.57E-06	35.17E-06	54.10E-06
<b>d(1/HFE) Lot WorstCase</b>	-	326.47E-06	647.10E-06	849.22E-06	1.12E-03	1.06E-03	857.40E-06

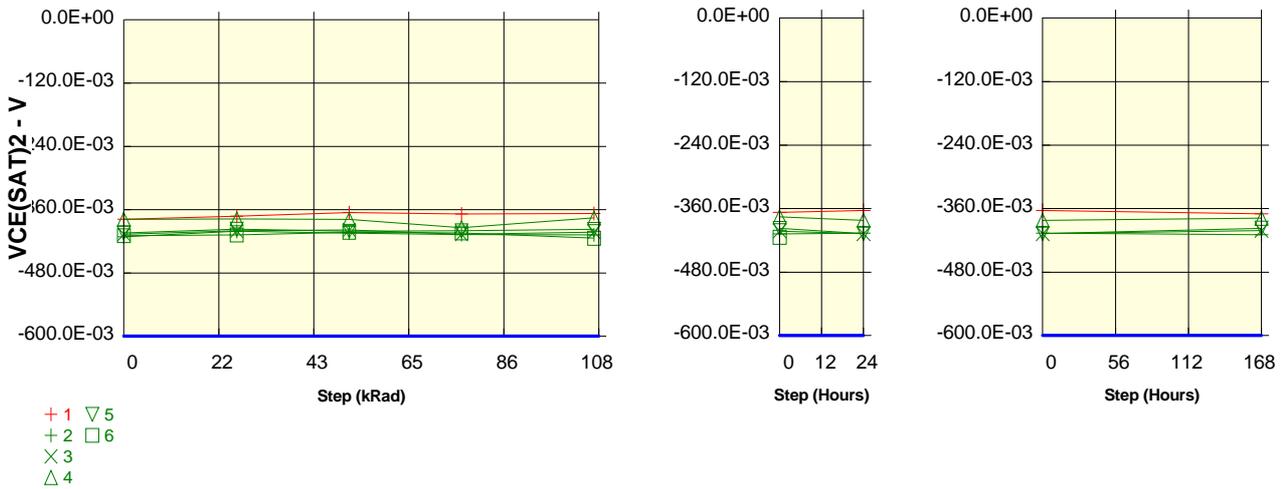
**Test conditions : TID**  
**Parameter : Collector emitter saturation voltage 1 : VCE(SAT)1**  
**Ic = -2A ; Ib = -100mA**  
 Unit : V  
 Spec Limit Min : -400.0E-03  
 Spec limits are represented in bold lines on the graphic.



Measurements							
VCE(SAT)1	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>1_REF</b>	-239.5E-03	-245.6E-03	-241.1E-03	-243.0E-03	-242.0E-03	-239.9E-03	-243.8E-03
<b>ON samples</b>							
2	-259.7E-03	-263.0E-03	-265.3E-03	-267.0E-03	-264.2E-03	-266.6E-03	-268.5E-03
3	-256.5E-03	-262.5E-03	-261.6E-03	-267.1E-03	-264.1E-03	-267.6E-03	-263.4E-03
4	-239.2E-03	-248.8E-03	-249.6E-03	-260.0E-03	-244.3E-03	-252.2E-03	-249.5E-03
5	-254.8E-03	-260.4E-03	-263.1E-03	-262.5E-03	-260.8E-03	-267.2E-03	-260.6E-03
6	-258.2E-03	-267.5E-03	-264.1E-03	-265.0E-03	-271.6E-03		
<b>Statistics</b>							
<b>Min</b>	-259.7E-03	-267.5E-03	-265.3E-03	-267.1E-03	-271.6E-03	-267.6E-03	-268.5E-03
<b>Max</b>	-239.2E-03	-248.8E-03	-249.6E-03	-260.0E-03	-244.3E-03	-252.2E-03	-249.5E-03
<b>Average</b>	-253.7E-03	-260.4E-03	-260.7E-03	-264.3E-03	-261.0E-03	-263.4E-03	-260.5E-03
<b>Sigma</b>	7.4E-03	6.3E-03	5.7E-03	2.7E-03	9.1E-03	6.5E-03	7.0E-03
<b>(VCE) Lot WorstCase</b>	-276.0E-03	-279.2E-03	-277.8E-03	-272.5E-03	-288.2E-03	-282.9E-03	-281.4E-03

Drift Calculation							
VCE(SAT)1	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
2	-	-3.28E-03	-5.60E-03	-7.32E-03	-4.48E-03	-6.92E-03	-8.80E-03
3	-	-6.00E-03	-5.08E-03	-10.60E-03	-7.64E-03	-11.16E-03	-6.92E-03
4	-	-9.68E-03	-10.44E-03	-20.88E-03	-5.16E-03	-13.00E-03	-10.32E-03
5	-	-5.60E-03	-8.36E-03	-7.72E-03	-6.04E-03	-12.40E-03	-5.84E-03
6	-	-9.28E-03	-5.84E-03	-6.76E-03	-13.36E-03		
<b>Average</b>	-	-6.77E-03	-7.06E-03	-10.66E-03	-7.34E-03	-10.87E-03	-7.97E-03
<b>Sigma</b>	-	2.40E-03	2.03E-03	5.28E-03	3.19E-03	2.38E-03	1.72E-03
<b>d(VCE) Lot WorstCase</b>	-	-13.98E-03	-13.16E-03	-26.50E-03	-16.91E-03	-18.00E-03	-13.13E-03

**Test conditions : TID**  
**Parameter : Collector emitter saturation voltage 2 : VCE(SAT)2**  
**Ic = -3A ; Ib = -150mA**  
 Unit : V  
 Spec Limit Min : -600.0E-03  
 Spec limits are represented in bold lines on the graphic.



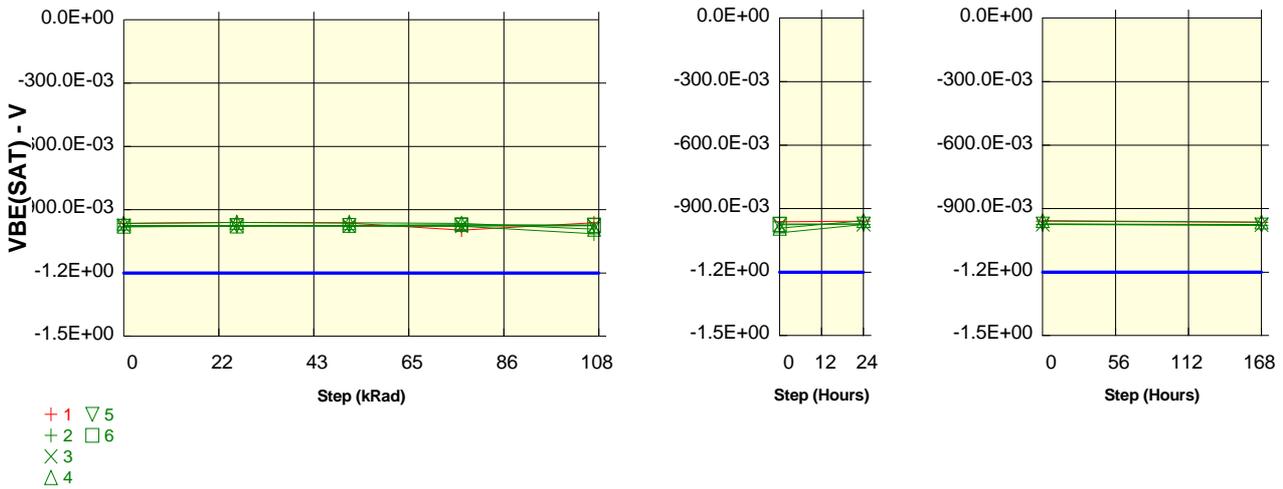
**Measurements**

VCE(SAT)2	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>1_REF</b>	-378.1E-03	-372.6E-03	-365.7E-03	-368.5E-03	-367.1E-03	-363.7E-03	-369.6E-03
<b>ON samples</b>							
<b>2</b>	-411.4E-03	-401.2E-03	-404.6E-03	-407.1E-03	-407.9E-03	-406.3E-03	-409.4E-03
<b>3</b>	-406.5E-03	-400.2E-03	-398.6E-03	-406.8E-03	-402.4E-03	-407.5E-03	-401.4E-03
<b>4</b>	-378.4E-03	-377.6E-03	-378.5E-03	-394.1E-03	-375.6E-03	-382.2E-03	-378.3E-03
<b>5</b>	-403.9E-03	-397.0E-03	-400.9E-03	-399.9E-03	-397.5E-03	-407.1E-03	-397.1E-03
<b>6</b>	-409.4E-03	-408.0E-03	-402.9E-03	-404.2E-03	-414.2E-03		
<b>Statistics</b>							
<b>Min</b>	-411.4E-03	-408.0E-03	-404.6E-03	-407.1E-03	-414.2E-03	-407.5E-03	-409.4E-03
<b>Max</b>	-378.4E-03	-377.6E-03	-378.5E-03	-394.1E-03	-375.6E-03	-382.2E-03	-378.3E-03
<b>Average</b>	-401.9E-03	-396.8E-03	-397.1E-03	-402.4E-03	-399.5E-03	-400.8E-03	-396.6E-03
<b>Sigma</b>	12.0E-03	10.2E-03	9.5E-03	4.9E-03	13.2E-03	10.7E-03	11.4E-03
<b>(VCE) Lot WorstCase</b>	-438.0E-03	-427.5E-03	-425.6E-03	-417.1E-03	-439.1E-03	-432.9E-03	-430.8E-03

**Drift Calculation**

VCE(SAT)2	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
<b>2</b>	-	10.24E-03	6.84E-03	4.28E-03	3.52E-03	5.08E-03	2.00E-03
<b>3</b>	-	6.36E-03	7.88E-03	-240.01E-06	4.12E-03	-960.01E-06	5.08E-03
<b>4</b>	-	760.01E-06	-120.00E-06	-15.72E-03	2.76E-03	-3.84E-03	80.01E-06
<b>5</b>	-	6.88E-03	3.00E-03	4.04E-03	6.40E-03	-3.16E-03	6.80E-03
<b>6</b>	-	1.40E-03	6.48E-03	5.20E-03	-4.80E-03		
<b>Average</b>	-	5.13E-03	4.82E-03	-487.99E-06	2.40E-03	-719.99E-06	3.49E-03
<b>Sigma</b>	-	3.57E-03	2.96E-03	7.84E-03	3.80E-03	3.51E-03	2.61E-03
<b>d(VCE) Lot WorstCase</b>	-	-5.58E-03	-4.07E-03	-24.02E-03	-9.00E-03	-11.26E-03	-4.35E-03

**Test conditions : TID**  
**Parameter : Base emitter saturation voltage : VBE(SAT)**  
**Ic = -2A ; Ib = -100mA**  
 Unit : V  
 Spec Limit Min : -1.2E+00  
 Spec limits are represented in bold lines on the graphic.



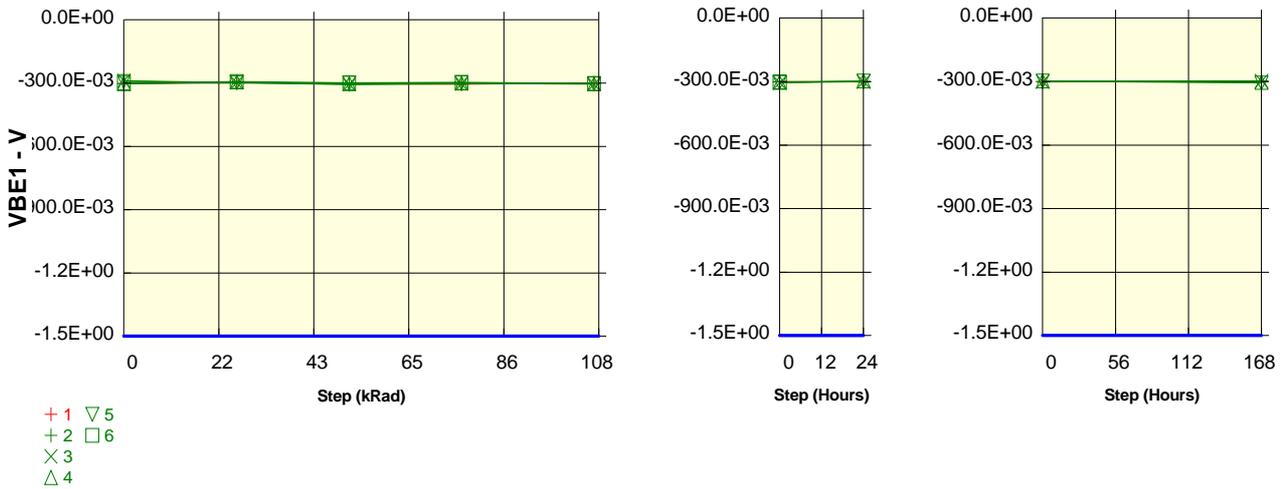
**Measurements**

VBE(SAT)	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>1_REF</b>	-964.8E-03	-961.0E-03	-963.0E-03	-997.3E-03	-962.2E-03	-960.2E-03	-964.3E-03
<b>ON samples</b>							
<b>2</b>	-982.2E-03	-977.3E-03	-977.6E-03	-978.7E-03	-1.0E+00	-975.6E-03	-978.8E-03
<b>3</b>	-975.7E-03	-976.3E-03	-977.8E-03	-977.3E-03	-976.4E-03	-973.0E-03	-975.7E-03
<b>4</b>	-964.3E-03	-960.4E-03	-961.6E-03	-964.5E-03	-992.6E-03	-957.3E-03	-963.8E-03
<b>5</b>	-977.6E-03	-976.0E-03	-975.4E-03	-974.1E-03	-972.5E-03	-972.8E-03	-977.8E-03
<b>6</b>	-979.3E-03	-977.2E-03	-974.8E-03	-971.6E-03	-975.0E-03		
<b>Statistics</b>							
<b>Min</b>	-982.2E-03	-977.3E-03	-977.8E-03	-978.7E-03	-1.0E+00	-975.6E-03	-978.8E-03
<b>Max</b>	-964.3E-03	-960.4E-03	-961.6E-03	-964.5E-03	-972.5E-03	-957.3E-03	-963.8E-03
<b>Average</b>	-975.8E-03	-973.4E-03	-973.4E-03	-973.2E-03	-986.2E-03	-969.7E-03	-974.0E-03
<b>Sigma</b>	6.2E-03	6.5E-03	6.1E-03	5.0E-03	15.9E-03	7.2E-03	6.0E-03
<b>(VBE) Lot WorstCase</b>	-994.3E-03	-993.1E-03	-991.6E-03	-988.3E-03	-1.0E+00	-991.3E-03	-992.0E-03

**Drift Calculation**

VBE(SAT)	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
<b>2</b>	-	4.96E-03	4.64E-03	3.52E-03	-32.36E-03	6.68E-03	3.48E-03
<b>3</b>	-	-640.05E-06	-2.12E-03	-1.60E-03	-720.04E-06	2.64E-03	-19.07E-09
<b>4</b>	-	3.88E-03	2.72E-03	-239.99E-06	-28.32E-03	6.96E-03	519.97E-06
<b>5</b>	-	1.56E-03	2.20E-03	3.48E-03	5.08E-03	4.76E-03	-239.99E-06
<b>6</b>	-	2.04E-03	4.44E-03	7.64E-03	4.28E-03		
<b>Average</b>	-	2.36E-03	2.38E-03	2.56E-03	-10.41E-03	5.26E-03	939.98E-06
<b>Sigma</b>	-	1.94E-03	2.44E-03	3.25E-03	16.45E-03	1.73E-03	1.49E-03
<b>d(VBE) Lot WorstCase</b>	-	-3.46E-03	-4.94E-03	-7.18E-03	-59.74E-03	59.35E-06	-3.54E-03

**Test conditions : TID**  
**Parameter : Base-Emitter Voltage : VBE1**  
**Vce = -2V ; Ic = -100nA**  
 Unit : V  
 Spec Limit Min : -1.5E+00  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

VBE1	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>1_REF</b>	-302.7E-03	-295.6E-03	-302.3E-03	-305.5E-03	-299.5E-03	-300.9E-03	-297.2E-03
<b>ON samples</b>							
<b>2</b>	-301.2E-03	-297.9E-03	-307.8E-03	-304.1E-03	-301.6E-03	-298.8E-03	-298.1E-03
<b>3</b>	-288.7E-03	-297.3E-03	-305.5E-03	-301.8E-03	-305.4E-03	-299.9E-03	-297.2E-03
<b>4</b>	-302.3E-03	-294.7E-03	-302.3E-03	-300.1E-03	-303.7E-03	-297.1E-03	-303.7E-03
<b>5</b>	-291.9E-03	-297.8E-03	-300.8E-03	-298.9E-03	-303.9E-03	-298.4E-03	-306.9E-03
<b>6</b>	-300.2E-03	-292.4E-03	-299.1E-03	-296.7E-03	-301.6E-03		
<b>Statistics</b>							
<b>Min</b>	-302.3E-03	-297.9E-03	-307.8E-03	-304.1E-03	-305.4E-03	-299.9E-03	-306.9E-03
<b>Max</b>	-288.7E-03	-292.4E-03	-299.1E-03	-296.7E-03	-301.6E-03	-297.1E-03	-297.2E-03
<b>Average</b>	-296.9E-03	-296.0E-03	-303.1E-03	-300.3E-03	-303.2E-03	-298.6E-03	-301.5E-03
<b>Sigma</b>	5.5E-03	2.2E-03	3.2E-03	2.5E-03	1.5E-03	999.7E-06	4.0E-03
<b>(VBE) Lot WorstCase</b>	-313.3E-03	-302.5E-03	-312.6E-03	-307.9E-03	-307.6E-03	-301.6E-03	-313.5E-03

**Drift Calculation**

VBE1	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
<b>2</b>	-	3.37E-03	-6.57E-03	-2.86E-03	-378.88E-06	2.44E-03	3.17E-03
<b>3</b>	-	-8.53E-03	-16.78E-03	-13.11E-03	-16.68E-03	-11.19E-03	-8.46E-03
<b>4</b>	-	7.54E-03	-26.40E-06	2.17E-03	-1.39E-03	5.16E-03	-1.45E-03
<b>5</b>	-	-5.87E-03	-8.88E-03	-6.99E-03	-11.94E-03	-6.48E-03	-14.96E-03
<b>6</b>	-	7.84E-03	1.06E-03	3.51E-03	-1.37E-03		
<b>Average</b>	-	867.50E-06	-6.24E-03	-3.46E-03	-6.35E-03	-2.52E-03	-5.42E-03
<b>Sigma</b>	-	6.83E-03	6.48E-03	6.10E-03	6.68E-03	6.60E-03	6.89E-03
<b>d(VBE) Lot WorstCase</b>	-	-19.62E-03	-25.68E-03	-21.77E-03	-26.39E-03	-22.32E-03	-26.09E-03

Test conditions : TID

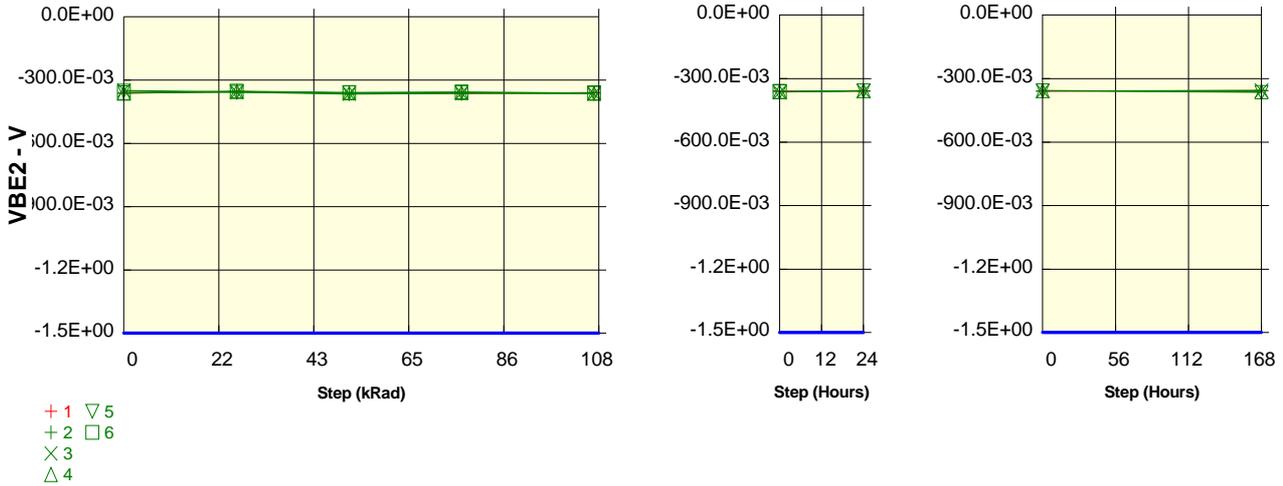
Parameter : Base-Emitter Voltage : VBE2

Vce = -2V ; Ic = -1µA

Unit : V

Spec Limit Min : -1.5E+00

Spec limits are represented in bold lines on the graphic.



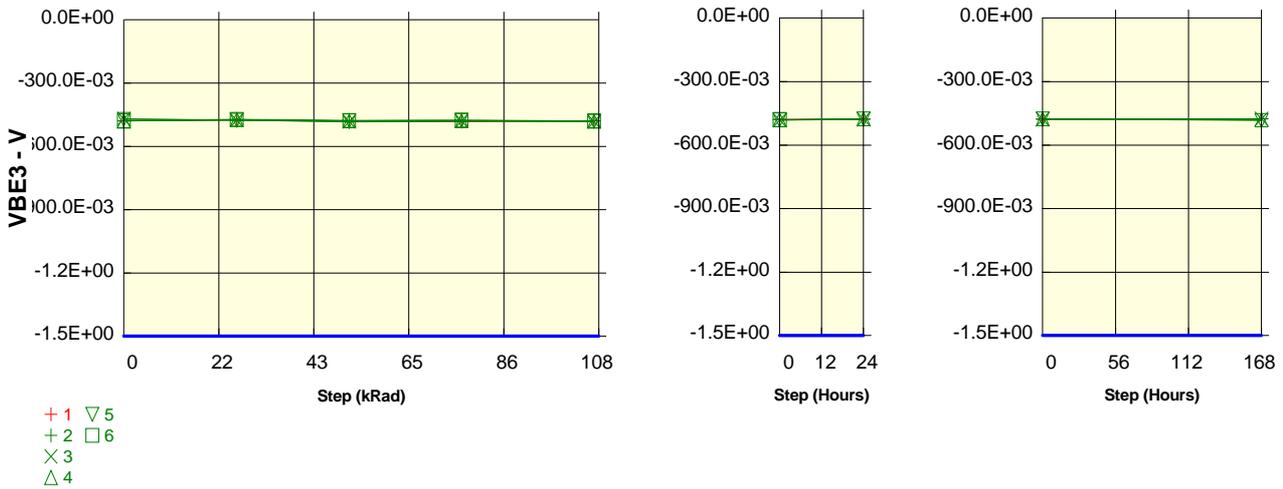
Measurements

VBE2	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
1_REF	-362.0E-03	-355.0E-03	-361.5E-03	-364.4E-03	-359.0E-03	-360.0E-03	-356.5E-03
ON samples							
2	-360.5E-03	-357.1E-03	-366.6E-03	-363.1E-03	-360.8E-03	-357.9E-03	-357.2E-03
3	-349.1E-03	-356.5E-03	-364.4E-03	-361.0E-03	-364.4E-03	-359.2E-03	-356.4E-03
4	-361.7E-03	-354.2E-03	-361.5E-03	-359.4E-03	-362.7E-03	-356.4E-03	-362.7E-03
5	-352.1E-03	-357.1E-03	-360.1E-03	-358.4E-03	-363.0E-03	-357.6E-03	-365.7E-03
6	-359.6E-03	-352.1E-03	-358.5E-03	-356.2E-03	-360.7E-03		
Statistics							
Min	-361.7E-03	-357.1E-03	-366.6E-03	-363.1E-03	-364.4E-03	-359.2E-03	-365.7E-03
Max	-349.1E-03	-352.1E-03	-358.5E-03	-356.2E-03	-360.7E-03	-356.4E-03	-356.4E-03
Average	-356.6E-03	-355.4E-03	-362.2E-03	-359.6E-03	-362.3E-03	-357.8E-03	-360.5E-03
Sigma	5.0E-03	2.0E-03	2.9E-03	2.3E-03	1.4E-03	989.6E-06	3.9E-03
(VBE) Lot WorstCase	-371.7E-03	-361.3E-03	-371.0E-03	-366.7E-03	-366.5E-03	-360.7E-03	-372.1E-03

Drift Calculation

VBE2	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
ON samples							
2	-	3.46E-03	-6.04E-03	-2.62E-03	-295.07E-06	2.60E-03	3.36E-03
3	-	-7.44E-03	-15.37E-03	-11.97E-03	-15.30E-03	-10.14E-03	-7.38E-03
4	-	7.46E-03	134.05E-06	2.25E-03	-1.08E-03	5.23E-03	-1.08E-03
5	-	-5.01E-03	-8.03E-03	-6.29E-03	-10.86E-03	-5.45E-03	-13.58E-03
6	-	7.49E-03	1.12E-03	3.38E-03	-1.13E-03		
Average	-	1.19E-03	-5.64E-03	-3.05E-03	-5.73E-03	-1.94E-03	-4.67E-03
Sigma	-	6.28E-03	5.99E-03	5.65E-03	6.17E-03	6.16E-03	6.40E-03
d(VBE) Lot WorstCase	-	-17.64E-03	-23.62E-03	-20.00E-03	-24.24E-03	-20.42E-03	-23.88E-03

**Test conditions : TID**  
**Parameter : Base-Emitter Voltage : VBE3**  
**Vce = -2V ; Ic = -100µA**  
 Unit : V  
 Spec Limit Min : -1.5E+00  
 Spec limits are represented in bold lines on the graphic.



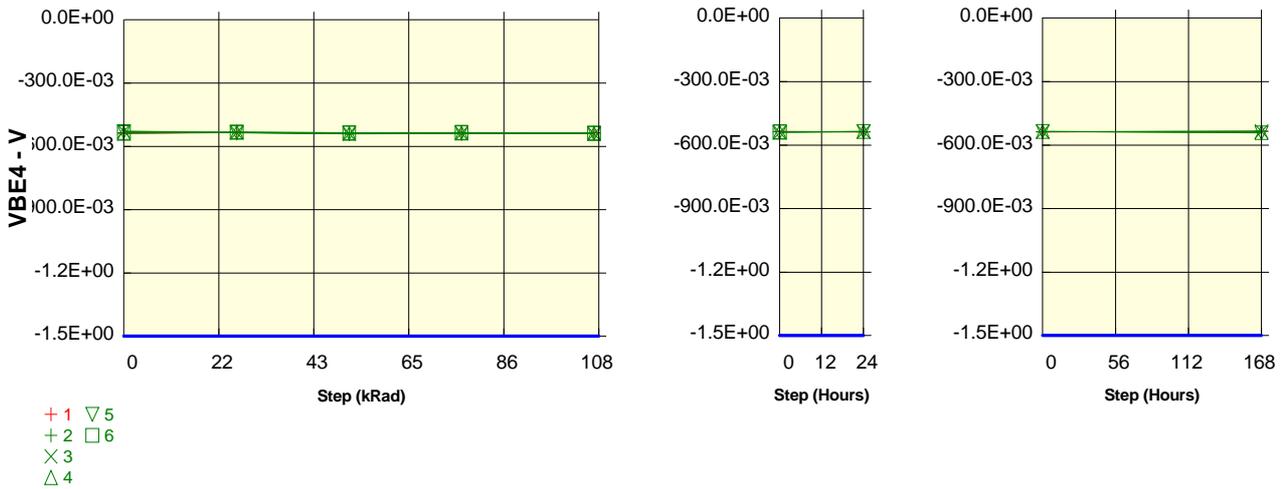
**Measurements**

VBE3	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>1_REF</b>	-480.2E-03	-474.1E-03	-479.8E-03	-482.3E-03	-477.7E-03	-478.5E-03	-475.4E-03
<b>ON samples</b>							
<b>2</b>	-478.9E-03	-475.7E-03	-484.0E-03	-481.1E-03	-479.2E-03	-476.6E-03	-475.7E-03
<b>3</b>	-469.3E-03	-475.4E-03	-482.3E-03	-479.5E-03	-482.4E-03	-477.7E-03	-475.4E-03
<b>4</b>	-480.0E-03	-473.4E-03	-479.8E-03	-478.1E-03	-481.0E-03	-475.4E-03	-480.8E-03
<b>5</b>	-471.8E-03	-475.9E-03	-478.6E-03	-477.2E-03	-481.2E-03	-476.3E-03	-483.3E-03
<b>6</b>	-478.0E-03	-471.5E-03	-477.0E-03	-475.1E-03	-479.0E-03		
<b>Statistics</b>							
<b>Min</b>	-480.0E-03	-475.9E-03	-484.0E-03	-481.1E-03	-482.4E-03	-477.7E-03	-483.3E-03
<b>Max</b>	-469.3E-03	-471.5E-03	-477.0E-03	-475.1E-03	-479.0E-03	-475.4E-03	-475.4E-03
<b>Average</b>	-475.6E-03	-474.4E-03	-480.4E-03	-478.2E-03	-480.6E-03	-476.5E-03	-478.8E-03
<b>Sigma</b>	4.2E-03	1.7E-03	2.5E-03	2.0E-03	1.3E-03	827.8E-06	3.4E-03
<b>(VBE) Lot WorstCase</b>	-488.3E-03	-479.5E-03	-487.9E-03	-484.4E-03	-484.4E-03	-479.0E-03	-489.0E-03

**Drift Calculation**

VBE3	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
<b>2</b>	-	3.19E-03	-5.08E-03	-2.23E-03	-279.49E-06	2.36E-03	3.19E-03
<b>3</b>	-	-6.06E-03	-13.00E-03	-10.17E-03	-13.04E-03	-8.40E-03	-6.06E-03
<b>4</b>	-	6.58E-03	196.07E-06	1.90E-03	-975.31E-06	4.61E-03	-775.19E-06
<b>5</b>	-	-4.10E-03	-6.79E-03	-5.36E-03	-9.37E-03	-4.47E-03	-11.50E-03
<b>6</b>	-	6.49E-03	1.03E-03	2.91E-03	-987.44E-06		
<b>Average</b>	-	1.22E-03	-4.73E-03	-2.59E-03	-4.93E-03	-1.47E-03	-3.79E-03
<b>Sigma</b>	-	5.32E-03	5.10E-03	4.81E-03	5.26E-03	5.21E-03	5.53E-03
<b>d(VBE) Lot WorstCase</b>	-	-14.75E-03	-20.03E-03	-17.02E-03	-20.70E-03	-17.10E-03	-20.39E-03

**Test conditions : TID**  
**Parameter : Base-Emitter Voltage : VBE4**  
**Vce = -2V ; Ic = -1mA**  
 Unit : V  
 Spec Limit Min : -1.5E+00  
 Spec limits are represented in bold lines on the graphic.



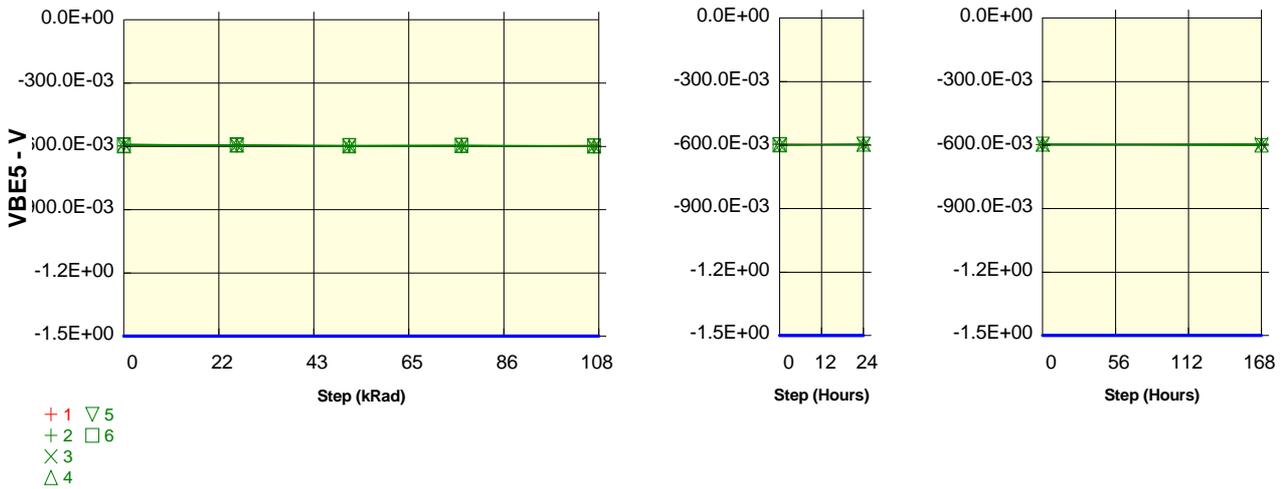
**Measurements**

VBE4	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>1_REF</b>	-537.9E-03	-533.7E-03	-537.9E-03	-540.1E-03	-535.5E-03	-537.5E-03	-534.9E-03
<b>ON samples</b>							
2	-536.1E-03	-535.0E-03	-541.3E-03	-539.0E-03	-537.2E-03	-536.8E-03	-534.7E-03
3	-528.2E-03	-534.6E-03	-540.0E-03	-537.6E-03	-539.9E-03	-537.2E-03	-535.3E-03
4	-537.5E-03	-533.1E-03	-537.9E-03	-536.3E-03	-538.7E-03	-535.3E-03	-540.3E-03
5	-530.0E-03	-535.4E-03	-536.7E-03	-535.7E-03	-539.0E-03	-535.7E-03	-542.3E-03
6	-534.4E-03	-531.4E-03	-535.2E-03	-533.8E-03	-536.9E-03		
<b>Statistics</b>							
<b>Min</b>	-537.5E-03	-535.4E-03	-541.3E-03	-539.0E-03	-539.9E-03	-537.2E-03	-542.3E-03
<b>Max</b>	-528.2E-03	-531.4E-03	-535.2E-03	-533.8E-03	-536.9E-03	-535.3E-03	-534.7E-03
<b>Average</b>	-533.2E-03	-533.9E-03	-538.2E-03	-536.5E-03	-538.3E-03	-536.2E-03	-538.1E-03
<b>Sigma</b>	3.6E-03	1.5E-03	2.2E-03	1.8E-03	1.1E-03	759.7E-06	3.2E-03
<b>(VBE) Lot WorstCase</b>	-543.9E-03	-538.4E-03	-544.8E-03	-541.8E-03	-541.8E-03	-538.5E-03	-547.9E-03

**Drift Calculation**

VBE4	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
2	-	1.04E-03	-5.24E-03	-2.96E-03	-1.12E-03	-679.97E-06	1.36E-03
3	-	-6.44E-03	-11.84E-03	-9.44E-03	-11.72E-03	-8.96E-03	-7.08E-03
4	-	4.40E-03	-400.01E-06	1.16E-03	-1.20E-03	2.20E-03	-2.80E-03
5	-	-5.36E-03	-6.64E-03	-5.64E-03	-8.96E-03	-5.68E-03	-12.28E-03
6	-	3.04E-03	-800.01E-06	599.98E-06	-2.44E-03		
<b>Average</b>	-	-664.01E-06	-4.98E-03	-3.26E-03	-5.09E-03	-3.28E-03	-5.20E-03
<b>Sigma</b>	-	4.42E-03	4.20E-03	3.96E-03	4.40E-03	4.32E-03	5.06E-03
<b>d(VBE) Lot WorstCase</b>	-	-13.92E-03	-17.59E-03	-15.13E-03	-18.29E-03	-16.25E-03	-20.38E-03

**Test conditions : TID**  
**Parameter : Base-Emitter Voltage : VBE5**  
**Vce = -2V ; Ic = -10mA**  
 Unit : V  
 Spec Limit Min : -1.5E+00  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

VBE5	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>1_REF</b>	-598.1E-03	-594.3E-03	-598.0E-03	-599.8E-03	-595.8E-03	-597.6E-03	-595.3E-03
<b>ON samples</b>							
<b>2</b>	-596.8E-03	-595.2E-03	-600.8E-03	-598.7E-03	-597.2E-03	-596.8E-03	-595.0E-03
<b>3</b>	-589.4E-03	-594.9E-03	-599.7E-03	-597.6E-03	-599.8E-03	-597.2E-03	-595.5E-03
<b>4</b>	-597.7E-03	-593.5E-03	-597.6E-03	-596.4E-03	-598.6E-03	-595.4E-03	-600.1E-03
<b>5</b>	-591.2E-03	-595.7E-03	-596.7E-03	-595.8E-03	-598.8E-03	-595.9E-03	-602.0E-03
<b>6</b>	-595.7E-03	-592.3E-03	-595.2E-03	-594.1E-03	-596.8E-03		
<b>Statistics</b>							
<b>Min</b>	-597.7E-03	-595.7E-03	-600.8E-03	-598.7E-03	-599.8E-03	-597.2E-03	-602.0E-03
<b>Max</b>	-589.4E-03	-592.3E-03	-595.2E-03	-594.1E-03	-596.8E-03	-595.4E-03	-595.0E-03
<b>Average</b>	-594.2E-03	-594.3E-03	-598.0E-03	-596.5E-03	-598.2E-03	-596.3E-03	-598.2E-03
<b>Sigma</b>	3.3E-03	1.2E-03	2.0E-03	1.6E-03	1.1E-03	708.5E-06	3.0E-03
<b>(VBE) Lot WorstCase</b>	-604.0E-03	-598.0E-03	-604.0E-03	-601.2E-03	-601.5E-03	-598.5E-03	-607.0E-03

**Drift Calculation**

VBE5	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
<b>2</b>	-	1.60E-03	-3.96E-03	-1.92E-03	-399.95E-06	0.00E+00	1.76E-03
<b>3</b>	-	-5.48E-03	-10.32E-03	-8.20E-03	-10.36E-03	-7.84E-03	-6.12E-03
<b>4</b>	-	4.20E-03	39.99E-06	1.24E-03	-960.05E-06	2.24E-03	-2.44E-03
<b>5</b>	-	-4.52E-03	-5.56E-03	-4.64E-03	-7.64E-03	-4.76E-03	-10.80E-03
<b>6</b>	-	3.40E-03	480.00E-06	1.60E-03	-1.04E-03		
<b>Average</b>	-	-160.00E-06	-3.86E-03	-2.38E-03	-4.08E-03	-2.59E-03	-4.40E-03
<b>Sigma</b>	-	4.05E-03	3.97E-03	3.69E-03	4.11E-03	3.95E-03	4.63E-03
<b>d(VBE) Lot WorstCase</b>	-	-12.32E-03	-15.76E-03	-13.46E-03	-16.42E-03	-14.43E-03	-18.29E-03

Test conditions : TID

Parameter : Base-Emitter Voltage : VBE6

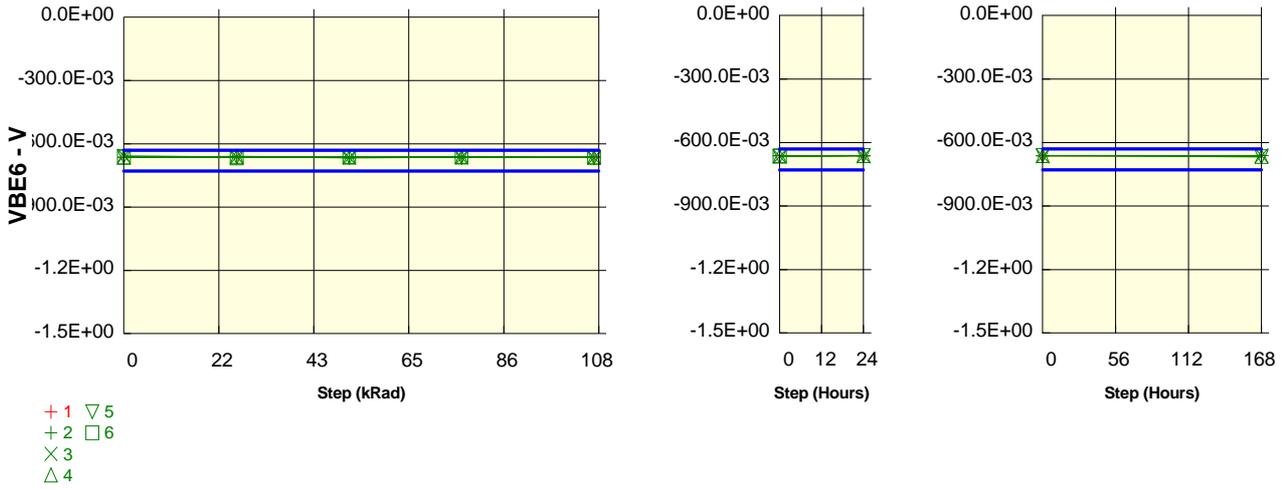
Vce = -2V ; Ic = -100mA

Unit : V

Spec Limit Min : -730.0E-03

Spec Limit Max : -630.0E-03

Spec limits are represented in bold lines on the graphic.



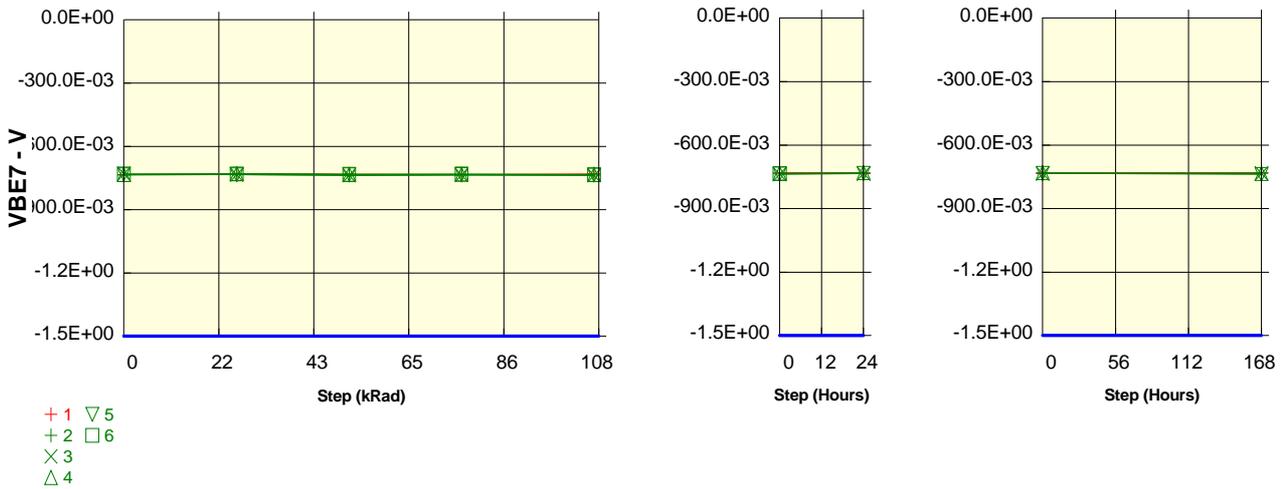
Measurements

VBE6	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
1_REF	-664.7E-03	-660.2E-03	-663.6E-03	-665.4E-03	-661.7E-03	-663.1E-03	-661.3E-03
ON samples							
2	-664.0E-03	-661.6E-03	-666.6E-03	-664.9E-03	-663.6E-03	-663.1E-03	-661.5E-03
3	-657.5E-03	-661.4E-03	-665.8E-03	-664.0E-03	-665.9E-03	-663.4E-03	-662.2E-03
4	-664.3E-03	-659.6E-03	-663.3E-03	-662.5E-03	-664.2E-03	-661.4E-03	-665.7E-03
5	-659.0E-03	-662.1E-03	-663.1E-03	-662.4E-03	-665.0E-03	-662.3E-03	-667.8E-03
6	-662.8E-03	-666.2E-03	-661.5E-03	-660.5E-03	-663.1E-03		
Statistics							
Min	-664.3E-03	-666.2E-03	-666.6E-03	-664.9E-03	-665.9E-03	-663.4E-03	-667.8E-03
Max	-657.5E-03	-659.6E-03	-661.5E-03	-660.5E-03	-663.1E-03	-661.4E-03	-661.5E-03
Average	-661.5E-03	-662.2E-03	-664.1E-03	-662.9E-03	-664.4E-03	-662.6E-03	-664.3E-03
Sigma	2.8E-03	2.2E-03	1.9E-03	1.5E-03	978.7E-06	804.0E-06	2.6E-03
(VBE) Lot WorstCase	-669.8E-03	-668.7E-03	-669.7E-03	-667.4E-03	-667.3E-03	-665.0E-03	-672.1E-03

Drift Calculation

VBE6	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
ON samples							
2	-	2.40E-03	-2.56E-03	-879.94E-06	400.01E-06	920.06E-06	2.52E-03
3	-	-3.96E-03	-8.36E-03	-6.56E-03	-8.40E-03	-5.96E-03	-4.68E-03
4	-	4.72E-03	999.99E-06	1.76E-03	39.99E-06	2.92E-03	-1.40E-03
5	-	-3.12E-03	-4.08E-03	-3.36E-03	-6.00E-03	-3.32E-03	-8.84E-03
6	-	-3.32E-03	1.36E-03	2.36E-03	-279.96E-06		
Average	-	-656.00E-06	-2.53E-03	-1.34E-03	-2.85E-03	-1.36E-03	-3.10E-03
Sigma	-	3.53E-03	3.58E-03	3.31E-03	3.64E-03	3.48E-03	4.18E-03
d(VBE) Lot WorstCase	-	-11.25E-03	-13.26E-03	-11.27E-03	-13.77E-03	-11.81E-03	-15.64E-03

**Test conditions : TID**  
**Parameter : Base-Emitter Voltage : VBE7**  
**Vce = -2V ; Ic = -500mA**  
 Unit : V  
 Spec Limit Min : -1.5E+00  
 Spec limits are represented in bold lines on the graphic.



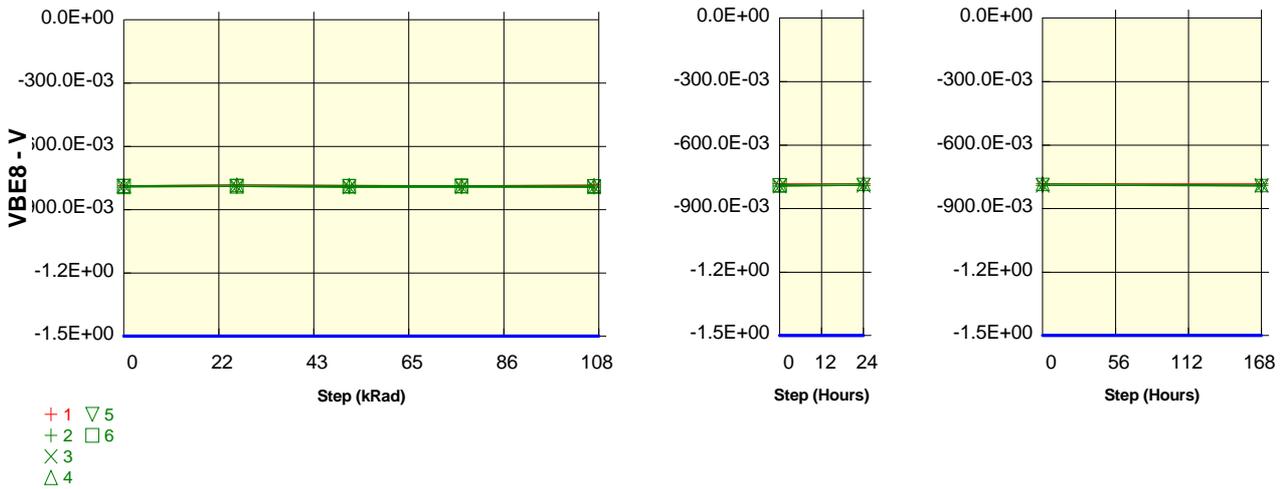
**Measurements**

VBE7	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>1_REF</b>	-733.5E-03	-729.2E-03	-732.3E-03	-733.8E-03	-730.0E-03	-730.7E-03	-730.0E-03
<b>ON samples</b>							
2	-736.2E-03	-733.6E-03	-737.4E-03	-736.3E-03	-735.9E-03	-734.3E-03	-733.5E-03
3	-730.2E-03	-733.8E-03	-737.3E-03	-735.7E-03	-737.1E-03	-734.4E-03	-733.7E-03
4	-733.3E-03	-729.6E-03	-732.4E-03	-732.2E-03	-733.1E-03	-730.0E-03	-734.5E-03
5	-731.5E-03	-734.2E-03	-734.6E-03	-733.7E-03	-735.7E-03	-733.4E-03	-738.6E-03
6	-734.5E-03	-730.9E-03	-732.8E-03	-731.4E-03	-734.3E-03		
<b>Statistics</b>							
Min	-736.2E-03	-734.2E-03	-737.4E-03	-736.3E-03	-737.1E-03	-734.4E-03	-738.6E-03
Max	-730.2E-03	-729.6E-03	-732.4E-03	-731.4E-03	-733.1E-03	-730.0E-03	-733.5E-03
Average	-733.1E-03	-732.4E-03	-734.9E-03	-733.9E-03	-735.2E-03	-733.0E-03	-735.1E-03
Sigma	2.1E-03	1.8E-03	2.1E-03	1.9E-03	1.4E-03	1.8E-03	2.1E-03
<b>(VBE) Lot WorstCase</b>	-739.5E-03	-738.0E-03	-741.3E-03	-739.5E-03	-739.3E-03	-738.4E-03	-741.3E-03

**Drift Calculation**

VBE7	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
2	-	2.52E-03	-1.20E-03	-160.04E-06	239.96E-06	1.88E-03	2.68E-03
3	-	-3.64E-03	-7.16E-03	-5.52E-03	-6.92E-03	-4.28E-03	-3.52E-03
4	-	3.72E-03	919.99E-06	1.04E-03	159.97E-06	3.28E-03	-1.24E-03
5	-	-2.68E-03	-3.12E-03	-2.16E-03	-4.16E-03	-1.88E-03	-7.08E-03
6	-	3.60E-03	1.72E-03	3.04E-03	160.03E-06		
Average	-	704.00E-06	-1.77E-03	-752.01E-06	-2.10E-03	-250.02E-06	-2.29E-03
Sigma	-	3.20E-03	3.18E-03	2.92E-03	2.94E-03	3.00E-03	3.54E-03
<b>d(VBE) Lot WorstCase</b>	-	-8.89E-03	-11.31E-03	-9.51E-03	-10.92E-03	-9.24E-03	-12.92E-03

**Test conditions : TID**  
**Parameter : Base-Emitter Voltage : VBE8**  
**Vce = -2V ; Ic = -1A**  
 Unit : V  
 Spec Limit Min : -1.5E+00  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

VBE8	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>1_REF</b>	-786.9E-03	-782.4E-03	-785.0E-03	-786.6E-03	-782.8E-03	-782.5E-03	-783.3E-03
<b>ON samples</b>							
2	-793.4E-03	-790.5E-03	-793.2E-03	-793.2E-03	-793.6E-03	-790.6E-03	-790.8E-03
3	-787.5E-03	-790.5E-03	-793.9E-03	-792.5E-03	-793.5E-03	-790.3E-03	-790.2E-03
4	-786.5E-03	-782.9E-03	-785.7E-03	-786.5E-03	-786.6E-03	-782.8E-03	-788.0E-03
5	-788.8E-03	-790.6E-03	-791.1E-03	-790.2E-03	-791.4E-03	-789.6E-03	-794.6E-03
6	-791.0E-03	-788.8E-03	-789.2E-03	-787.4E-03	-790.8E-03		
<b>Statistics</b>							
<b>Min</b>	-793.4E-03	-790.6E-03	-793.9E-03	-793.2E-03	-793.6E-03	-790.6E-03	-794.6E-03
<b>Max</b>	-786.5E-03	-782.9E-03	-785.7E-03	-786.5E-03	-786.6E-03	-782.8E-03	-788.0E-03
<b>Average</b>	-789.4E-03	-788.6E-03	-790.6E-03	-790.0E-03	-791.2E-03	-788.3E-03	-790.9E-03
<b>Sigma</b>	2.5E-03	3.0E-03	3.0E-03	2.6E-03	2.6E-03	3.2E-03	2.4E-03
<b>(VBE) Lot WorstCase</b>	-796.8E-03	-797.5E-03	-799.5E-03	-797.9E-03	-798.9E-03	-797.9E-03	-798.1E-03

**Drift Calculation**

VBE8	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
<b>ON samples</b>							
2	-	2.84E-03	119.97E-06	199.96E-06	-280.03E-06	2.76E-03	2.56E-03
3	-	-2.96E-03	-6.36E-03	-4.96E-03	-6.00E-03	-2.76E-03	-2.64E-03
4	-	3.60E-03	800.00E-06	-40.00E-06	-80.00E-06	3.68E-03	-1.48E-03
5	-	-1.80E-03	-2.36E-03	-1.44E-03	-2.60E-03	-840.02E-06	-5.84E-03
6	-	2.20E-03	1.76E-03	3.56E-03	160.03E-06		
<b>Average</b>	-	775.99E-06	-1.21E-03	-536.01E-06	-1.76E-03	709.99E-06	-1.85E-03
<b>Sigma</b>	-	2.64E-03	2.91E-03	2.76E-03	2.34E-03	2.62E-03	3.01E-03
<b>d(VBE) Lot WorstCase</b>	-	-7.14E-03	-9.95E-03	-8.80E-03	-8.78E-03	-7.15E-03	-10.87E-03

Test conditions : TID

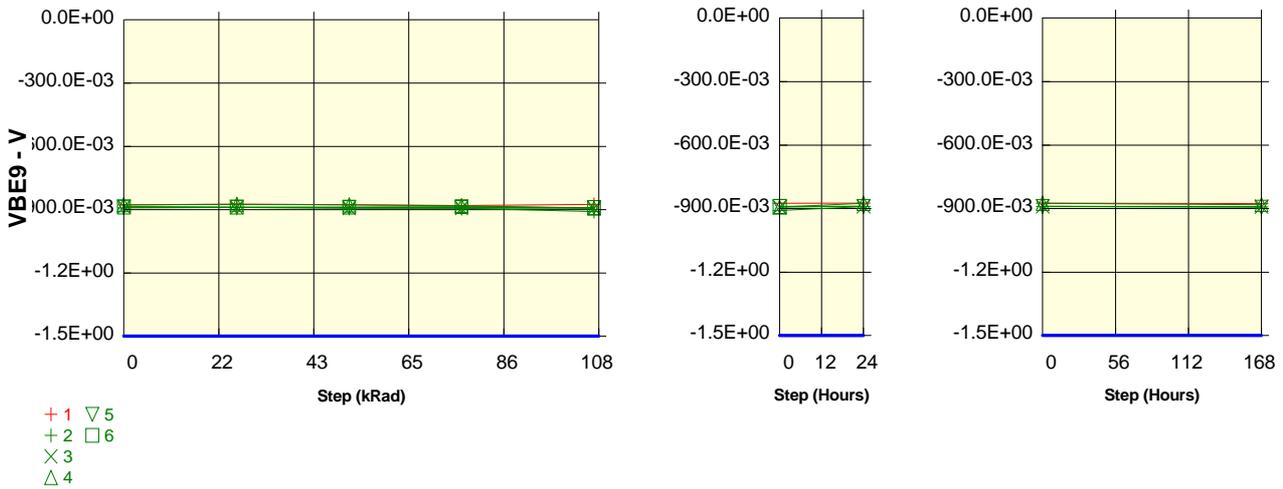
Parameter : Base-Emitter Voltage : VBE9

Vce = -2V ; Ic = -2A

Unit : V

Spec Limit Min : -1.5E+00

Spec limits are represented in bold lines on the graphic.



Measurements

VBE9	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
1_REF	-877.6E-03	-873.7E-03	-876.8E-03	-879.8E-03	-875.5E-03	-873.8E-03	-876.9E-03
ON samples							
2	-892.4E-03	-889.5E-03	-891.7E-03	-893.6E-03	-908.6E-03	-891.2E-03	-892.5E-03
3	-886.3E-03	-889.2E-03	-892.8E-03	-892.8E-03	-893.6E-03	-889.6E-03	-890.8E-03
4	-877.2E-03	-875.2E-03	-878.0E-03	-881.6E-03	-893.0E-03	-875.7E-03	-881.8E-03
5	-887.3E-03	-889.0E-03	-889.7E-03	-889.4E-03	-889.4E-03	-889.1E-03	-893.8E-03
6	-888.4E-03	-888.3E-03	-888.1E-03	-885.4E-03	-890.2E-03		
Statistics							
Min	-892.4E-03	-889.5E-03	-892.8E-03	-893.6E-03	-908.6E-03	-891.2E-03	-893.8E-03
Max	-877.2E-03	-875.2E-03	-878.0E-03	-881.6E-03	-889.4E-03	-875.7E-03	-881.8E-03
Average	-886.3E-03	-886.2E-03	-888.1E-03	-888.6E-03	-895.0E-03	-886.4E-03	-889.7E-03
Sigma	5.0E-03	5.5E-03	5.3E-03	4.5E-03	7.0E-03	6.2E-03	4.7E-03
(VBE) Lot WorstCase	-901.3E-03	-902.8E-03	-903.9E-03	-902.1E-03	-915.9E-03	-905.1E-03	-903.8E-03

Drift Calculation

VBE9	0 kRad	25.9 kRad	51.7 kRad	77.5 kRad	107.9 kRad	24 Hours	168 Hours
ON samples							
2	-	2.92E-03	720.01E-06	-1.20E-03	-16.12E-03	1.20E-03	-40.01E-06
3	-	-2.84E-03	-6.48E-03	-6.44E-03	-7.28E-03	-3.28E-03	-4.48E-03
4	-	2.08E-03	-800.03E-06	-4.40E-03	-15.72E-03	1.56E-03	-4.56E-03
5	-	-1.68E-03	-2.44E-03	-2.16E-03	-2.12E-03	-1.80E-03	-6.56E-03
6	-	120.04E-06	280.00E-06	3.00E-03	-1.84E-03		
Average	-	120.02E-06	-1.74E-03	-2.24E-03	-8.62E-03	-580.00E-06	-3.91E-03
Sigma	-	2.18E-03	2.61E-03	3.19E-03	6.27E-03	2.03E-03	2.38E-03
d(VBE) Lot WorstCase	-	-6.41E-03	-9.56E-03	-11.81E-03	-27.43E-03	-6.68E-03	-11.06E-03